



US005953284A

United States Patent [19]
Baker et al.

[11] **Patent Number:** **5,953,284**
[45] **Date of Patent:** ***Sep. 14, 1999**

[54] **METHOD AND APPARATUS FOR ADAPTIVELY ADJUSTING THE TIMING OF A CLOCK SIGNAL USED TO LATCH DIGITAL SIGNALS, AND MEMORY DEVICE USING SAME**

- 0 406 786 A1 1/1991 European Pat. Off. .
- 0 450 871 A2 10/1991 European Pat. Off. .
- 0 476 585 A2 3/1992 European Pat. Off. .
- 0 655 741 A2 5/1995 European Pat. Off. .
- 0 655 834 A1 5/1995 European Pat. Off. .
- 0 680 049 A2 11/1995 European Pat. Off. .
- 0 703 663 A1 3/1996 European Pat. Off. .

(List continued on next page.)

[75] Inventors: **Russel Jacob Baker; Troy A. Manning**, both of Meridian, Id.

[73] Assignee: **Micron Technology, Inc.**, Boise, Id.

OTHER PUBLICATIONS

[*] Notice: This patent issued on a continued prosecution application filed under 37 CFR 1.53(d), and is subject to the twenty year patent term provisions of 35 U.S.C. 154(a)(2).

- Alvarez, J. et al. "A Wide-Bandwidth Low Voltage PLL for PowerPC™ Microprocessors" IEEE IEICE Trans. Electron., vol. E-78. No. 6, Jun. 1995, pp. 631-639.
- Aviram, A. et al., "Obtaining High Speed Printing on Thermal Sensitive Special Paper with a Resistive Ribbon Print Head", IBM Technical Disclosure Bulletin, vol. 27, No. 5, Oct. 1984, pp. 3059-3060.
- Chapman, J. et al., "A Low-Cost High-Performance CMOS Timing Vernier for ATE", IEEE International Test Conference, Paper 21.2, 1995, pp. 459-468.

(List continued on next page.)

[21] Appl. No.: **08/890,055**

[22] Filed: **Jul. 9, 1997**

[51] **Int. Cl.⁶** **G11C 7/00**

[52] **U.S. Cl.** **365/233; 365/240; 365/230.08; 365/189.12**

[58] **Field of Search** **365/233, 230.08, 365/240, 230.02, 189.05, 189.12**

Primary Examiner—Vu A. Le
Attorney, Agent, or Firm—Seed and Berry LLP

[57] **ABSTRACT**

A system for adjusting the phase of an internal clock signal relative to an external clock signal in a packetized dynamic random access memory device. The system applies a plurality of initialization packets to the memory device that are captured in a shift register responsive to a transition of the internal clock signal. However, the phase of the internal clock signal is sequentially incremented after each initialization packet has been captured in the shift register. After a plurality of initialization packets have been captured, an evaluation circuit identifies which phases of the internal clock signal clocked the shift register at the proper time to accurately capture each initialization packet. A single phase of the internal clock signal is then selected from within the range of internal clock signal phases that successfully captured initialization packets. This selected phase of the internal clock signal is used during normal operation of the memory device.

[56] **References Cited**

U.S. PATENT DOCUMENTS

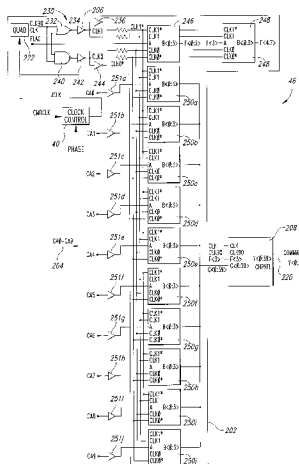
- 3,633,174 1/1972 Griffin 340/172.5
- 4,077,016 2/1978 Sanders et al. 331/4
- 4,096,402 6/1978 Schroeder et al. 307/362
- 4,404,474 9/1983 Dingwall 307/260
- 4,511,846 4/1985 Nagy et al. 328/164
- 4,514,647 4/1985 Shoji 307/269
- 4,600,895 7/1986 Landsman 331/1 A
- 4,638,187 1/1987 Boler et al. 307/451
- 4,687,951 8/1987 McElroy 307/269
- 4,773,085 9/1988 Cordell 375/120
- 4,789,796 12/1988 Foss 307/443
- 4,893,087 1/1990 Davis 328/14

(List continued on next page.)

FOREIGN PATENT DOCUMENTS

0 295 515 A1 12/1988 European Pat. Off. .

64 Claims, 17 Drawing Sheets



U.S. PATENT DOCUMENTS

4,902,986	2/1990	Lesmeister	331/25
4,958,088	9/1990	Farah-Bakhsh et al.	307/443
4,984,204	1/1991	Sato et al.	365/189.11
5,020,023	5/1991	Smith	364/900
5,038,115	8/1991	Myers et al.	331/2
5,086,500	2/1992	Greub	395/550
5,087,828	2/1992	Sato et al.	307/269
5,122,690	6/1992	Bianchi	307/475
5,128,560	7/1992	Chern et al.	307/475
5,128,563	7/1992	Hush et al.	307/482
5,134,311	7/1992	Biber et al.	307/270
5,150,186	9/1992	Pinney et al.	357/42
5,165,046	11/1992	Hesson	307/270
5,179,298	1/1993	Hirano et al.	307/443
5,194,765	3/1993	Dunlop et al.	307/443
5,220,208	6/1993	Schenck	307/443
5,239,206	8/1993	Yanai	307/272.2
5,243,703	9/1993	Farmwald et al.	395/325
5,254,883	10/1993	Horowitz et al.	307/443
5,256,989	10/1993	Parker et al.	331/1 A
5,257,294	10/1993	Pinto et al.	375/120
5,268,639	12/1993	Gasbarro et al.	324/158 R
5,276,642	1/1994	Lee	365/189.04
5,278,460	1/1994	Casper	307/296.5
5,281,865	1/1994	Yamashita et al.	307/279
5,283,631	2/1994	Koerner et al.	307/451
5,295,164	3/1994	Yamamura	375/120
5,311,481	5/1994	Casper et al.	365/230.06
5,321,368	6/1994	Hoelzle	328/63
5,337,285	8/1994	Ware et al.	365/227
5,347,177	9/1994	Lipp	307/443
5,347,179	9/1994	Casper et al.	307/451
5,355,391	10/1994	Horowitz et al.	375/36
5,361,002	11/1994	Casper	327/530
5,390,308	2/1995	Ware et al.	395/400
5,400,283	3/1995	Raad	365/203
5,408,640	4/1995	MacIntyre et al.	395/550
5,416,436	5/1995	Rainard	327/270
5,420,544	5/1995	Ishibashi	331/11
5,428,311	6/1995	McClure	327/276
5,430,676	7/1995	Ware et al.	365/189.02
5,432,823	7/1995	Gasbarro et al.	375/356
5,438,545	8/1995	Sim	365/189.05
5,440,260	8/1995	Hayashi et al.	327/278
5,440,514	8/1995	Flannagan et al.	365/194
5,446,696	8/1995	Ware et al.	365/222
5,448,193	9/1995	Baumert et al.	327/156
5,451,898	9/1995	Johnson	327/563
5,457,407	10/1995	Shu et al.	326/30
5,473,274	12/1995	Reilly et al.	327/159
5,473,575	12/1995	Farmwald et al.	365/230.06
5,473,639	12/1995	Lee et al.	375/376
5,485,490	1/1996	Leung et al.	375/371
5,488,321	1/1996	Johnson	327/66
5,497,127	3/1996	Sauer	331/17
5,498,990	3/1996	Leung et al.	327/323
5,506,814	4/1996	Hush et al.	365/230.03
5,508,638	4/1996	Cowles et al.	326/38
5,513,327	4/1996	Farmwald et al.	395/309
5,539,345	7/1996	Hawkins	327/150
5,552,727	9/1996	Nakao	327/159
5,568,077	10/1996	Sato et al.	327/199
5,572,557	11/1996	Aoki	375/376
5,574,698	11/1996	Raad	365/230.06
5,576,645	11/1996	Farwell	327/94
5,577,236	11/1996	Johnson et al.	395/551
5,578,940	11/1996	Dillon et al.	326/30
5,578,941	11/1996	Sher et al.	326/34
5,579,326	11/1996	McClure	371/61
5,581,197	12/1996	Motley et al.	326/30

5,589,788	12/1996	Goto	327/276
5,590,073	12/1996	Arakawa et al.	365/185.05
5,594,690	1/1997	Rothenberger et al.	365/189.01
5,614,855	3/1997	Lee et al.	327/158
5,619,473	4/1997	Hotta	365/238.5
5,621,340	4/1997	Lee et al.	327/65
5,621,690	4/1997	Jungroth et al.	365/200
5,621,739	4/1997	Sine et al.	371/22.1
5,627,780	5/1997	Malhi	365/185.09
5,627,791	5/1997	Wright et al.	365/222
5,631,872	5/1997	Naritake et al.	365/227
5,636,163	6/1997	Furutani et al.	365/189.01
5,636,173	6/1997	Schaefer	365/230.03
5,636,174	6/1997	Rao	365/230.03
5,638,335	6/1997	Akiyama et al.	365/230.03
5,657,481	8/1997	Farmwald et al.	395/551
5,668,763	9/1997	Fujioka et al.	365/200
5,692,165	11/1997	Jeddeloh et al.	395/551
5,694,065	12/1997	Hamasaki et al.	327/108
5,712,580	1/1998	Baumgartner et al.	327/12
5,751,665	5/1998	Tanoi	368/120
5,767,715	6/1998	Marquis et al.	365/233
5,781,499	7/1998	Koshikawa	365/233

FOREIGN PATENT DOCUMENTS

0 704 848 A2	4/1996	European Pat. Off.	.
0 704 975 A1	4/1996	European Pat. Off.	.
0 767 538 A1	4/1997	European Pat. Off.	.
6-1237512	10/1986	Japan	.
2-112317	4/1990	Japan	.
4-135311	8/1992	Japan	.
5-136664	6/1993	Japan	.
5-282868	10/1993	Japan	.
0-7319577	12/1995	Japan	.
WO 94/29871	12/1994	WIPO	G11C 7/00
WO 95/22200	8/1995	WIPO	H03H 11/20
WO			
95/9522206	8/1995	WIPO	H03L 7/081
WO 96/10866	4/1996	WIPO	.
WO 97/14289	4/1997	WIPO	.
WO 97/42557	11/1997	WIPO	.

OTHER PUBLICATIONS

Cho, J. "Digitally-Controlled PLL with Pulse Width Detection Mechanism for Error Correction", ISSCC 1997, Paper No. SA 20.3, pp. 334-335.

Christiansen, J., "An Integrated High Resolution CMOS Timing Generator Based on an Array of Delay Locked Loops", IEEE Journal of Solid-State Circuits, vol. 31, No. 7, Jul. 1996, pp. 952-957.

Combes, M. et al., "A Portable Clock Multiplier Generator Using Digital CMOS Standard Cells", IEEE Journal of Solid-State Circuits, vol. 31, No. 7, Jul. 1996, pp. 958-965.

"Draft Standard for a High-Speed Memory Interface (SyncLink)", Microprocessor and Microcomputer Standards Subcommittee of the IEEE Computer Society, Copyright 1996 by the Institute of Electrical and Electronics Engineers, Inc., New York, NY, pp. 1-56.

Goto, J. et al., "A PLL-Based Programmable Clock Generator with 50- to 350-MHz Oscillating Range for Video Signal Processors", IEICE Trans. Electron., vol. E77-C, No. 12, Dec. 1994, pp. 1951-1956.

Ishibashi, A. et al., "High-Speed Clock Distribution Architecture Employing PLL for 0.6 μ m CMOS SOG", IEEE Custom Integrated Circuits Conference, 1992, pp. 27.6.1-27.6.4.

Kim, B. et al., "A 30MHz High-Speed Analog/Digital PLL in 2 μ m CMOS", ISSCC, Feb. 1990.

- Kitkuchi, S. et al., "A Gate-Array-Based 666MHz VLSI Test System", IEEE International Test Conference, Paper 21.1, 1995, pp. 451-458.
- Ko, U. et al., "A 30-ps Jitter, 3.6- β s Locking, 3.3-Volt Digital PLL for CMOS Gate Arrays", IEEE Custom Integrated Circuits Conference, 1993, pp. 23.3.1-23.3.4.
- Lee, T. et al., "A 2.5V Delay-Locked Loop for an 18Mb 500MB/s Dram", IEEE International Solid-State Circuits Conference Digest of Technical Papers, Paper No. FA 18.6, 1994, pp. 300-301.
- Lesmeister, G., "A Densely Integrated High Performance CMOS Tester", International Test Conference, Paper 16.2, 1991, pp. 426-429.
- Ljuslin, C. et al., "An Integrated 16-channel CMOS Time to Digital Converter", IEEE Nuclear Science Symposium & Medical Imaging Conference Record, vol. 1, 1993, pp. 625-629.
- Maneatis, J., "Low-Jitter Process-Independent DLL and PLL Based on Self-Biased Techniques", IEEE Journal of Solid-State Circuits, vol. 31, No. 11, Nov. 1996, pp. 1723-1732.
- Nakamura, M. et al., "A 156 Mbps CMOS Clock Recovery Circuit for Burst-mode Transmission", Symposium on VLSI Circuits Digest of Technical Papers, 1996, pp. 122-123.
- Nielson, E., "Inverting latches make simple VCO", EDN, Jun. 19, 1997.
- Novof, I. et al., "Fully Integrated CMOS Phase-Locked Loop with 15 to 240 MHz Locking Range and ± 50 ps Jitter", IEEE Journal of Solid-State Circuits, vol. 30, No. 11, Nov. 1995, pp. 1259-1266.
- Santos, D. et al., "A CMOS Delay Locked Loop And Sub-Nanosecond Time-to-Digital Converter Chip", IEEE Nuclear Science Symposium and Medical Imaging Conference Record, vol. 1, Oct. 1995, pp. 289-291.
- Saeki, T. et al., "A 2.5-ns Clock Access, 250-MHz, 256-Mb SDRAM with Synchronous Mirror Delay", IEEE Journal of Solid-State Circuits, vol. 31, No. 11, Nov. 1996, pp. 1656-1665.
- Shirotori, T. et al., "PLL-based, Impedance Controlled Output Buffer", 1991 Symposium on VLSI Circuits Digest of Technical Papers, pp. 49-50.
- Descriptive literature entitled, "400MHz SLDRAM, 4M X 16 SLDRAM Pipelined, Eight Bank, 2.5 V Operation," SLDRAM Consortium Advance Sheet, published throughout the United States, pp. 1-22.
- Sidiropoulos, S. et al., "A 700-Mb/s/pin CMOS Signaling Interface Using Current Integrating Receivers", IEEE Journal of Solid-State Circuits, vol. 32, No. 5, May 1997, pp. 681-690.
- Sidiropoulos, S. et al., "A CMOS 500 Mbps/pin synchronous point to point link interface", IEEE Symposium on VLSI Circuits Digest of Technical Papers, 1994, pp. 43-44.
- Sidiropoulos, S. et al., "A Semi-Digital DLL with Unlimited Phase Shift Capability and 0.08-400MHz Operating Range," in *1997 IEEE International Solid State Circuits Conference*, Feb. 8, 1997, pp. 332-333.
- Soyuer, M. et al., "A Fully Monolithic 1.25 GHz CMOS Frequency Synthesizer", IEEE Symposium on VLSI Circuits Digest of Technical Papers, 1994, pp. 127-128.
- Tanoi, S. et al., "A 250-622 MHz Deskew and Jitter-Suppressed Clock Buffer Using a Frequency- and Delay-Locked Two-Loop Architecture", 1995 Symposium on VLSI Circuits Digest of Technical Papers, vol. 11, No. 2, pp. 85-86.
- Tanoi, S. et al., "A 250-622 MHz Deskew and Jitter-Suppressed Clock Buffer Using Two-Loop Architecture", IEEE IEICE Trans. Electron., vol. E-79-C. No. 7, Jul. 1996, pp. 898-904.
- von Kaenel, V. et al., "A 320 MHz, 1.5mW @ V CMOS PLL for Microprocessor Clock Generation", IEEE Journal of Solid-State Circuits, vol. 31, No. 11, Nov. 1996, pp. 1715-1722.
- Watson, R. et al., "Clock Buffer Chip with Absolute Delay Regulation Over Process and Environmental Variations", IEEE Custom Integrated Circuits Conference, 1992, pp. 25.2.1-25.2.5.
- Yoshimura, T. et al., "A 622-Mbps CMOS Clock Recovery Circuit for Burst-Mode Transmission", Symposium on VLSI Circuits Digest of Technical Papers, 1996, pp. 122-123.
- Yoshimura, T. et al., "A 622-Mb/s Bit/Frame Synchronizer for High-Speed Backplane Data Communication", IEEE Journal of Solid-State Circuits, vol. 31, No. 7, Jul. 1996, pp. 1063-1066.
- Arai, Y. et al., "A CMOS Four Channel \times 1K Time Memory LSI with 1-ns/b Resolution", IEEE Journal of Solid-State Circuits, vol. 27, No. 3, Mar. 1992, No. 3, New York, US.
- Arai, Y. et al., "A Time Digitizer CMOS Gate-Array with a 250 ps Time Resolution", XP 000597207, IEEE Journal of Solid-State Circuits, vol. 31, No. 2, Feb. 1996.
- Bazes, M., "Two Novel Fully Complementary Self-Biased CMOS Differential Amplifiers", IEEE Journal of Solid-State Circuits, vol. 26, No. 2, Feb. 1991, pp. 165-168.
- Donnelly, K. et al., "A 660 MB/s Interface Megacell Portable Circuit in 0.3 μ m-0.7 μ m CMOS ASIC", IEEE Journal of Solid-State Circuits, vol. 31, No. 12, Dec. 1996, pp. 1995-2001.
- Descriptive literature entitled, "400 MHz SLDRAM, 4M \times 16 SLDRAM Pipelined, Eight Bank, 2.5 V Operation," pp. 1-22.
- "Draft Standard for a High-Speed Memory Interface (SyncLink)," Microprocessor and Microcomputer Standards Subcommittee of the IEEE Computer Society, Copyright 1996 by the Institute of Electrical and Electronics Engineers, Inc., New York, NY, pp. 1-56.
- Anonymous, "Programmable Pulse Generator", IBM Technical Disclosure Bulletin, vol. 17, No. 12, May 1975, pp. 3553-3554.
- Anonymous, "Pulse Combining Network", IBM Technical Disclosure Bulletin, vol. 32, No. 12, May 1990, pp. 149-151.
- Anonymous, "Variable Delay Digital Circuit", IBM Technical Disclosure Bulletin, vol. 35, No. 4A, Sep. 1992, pp. 365-366.
- Hamamoto, T., "400-MHz Random Column Operating SDRAM Techniques with Self-Skew Compensation, IEEE Journal of Solid-State Circuits, vol. 33, No. 5, May 1998 pp. 770-778.
- Taguchi, M. et al., "A 40-ns 64-Mb DRAM with 64-b Parallel Data Bus Architecture", IEEE Journal of Solid-State Circuits, vol. 26, No. 11, Nov. 1991, pp. 1493-1497.

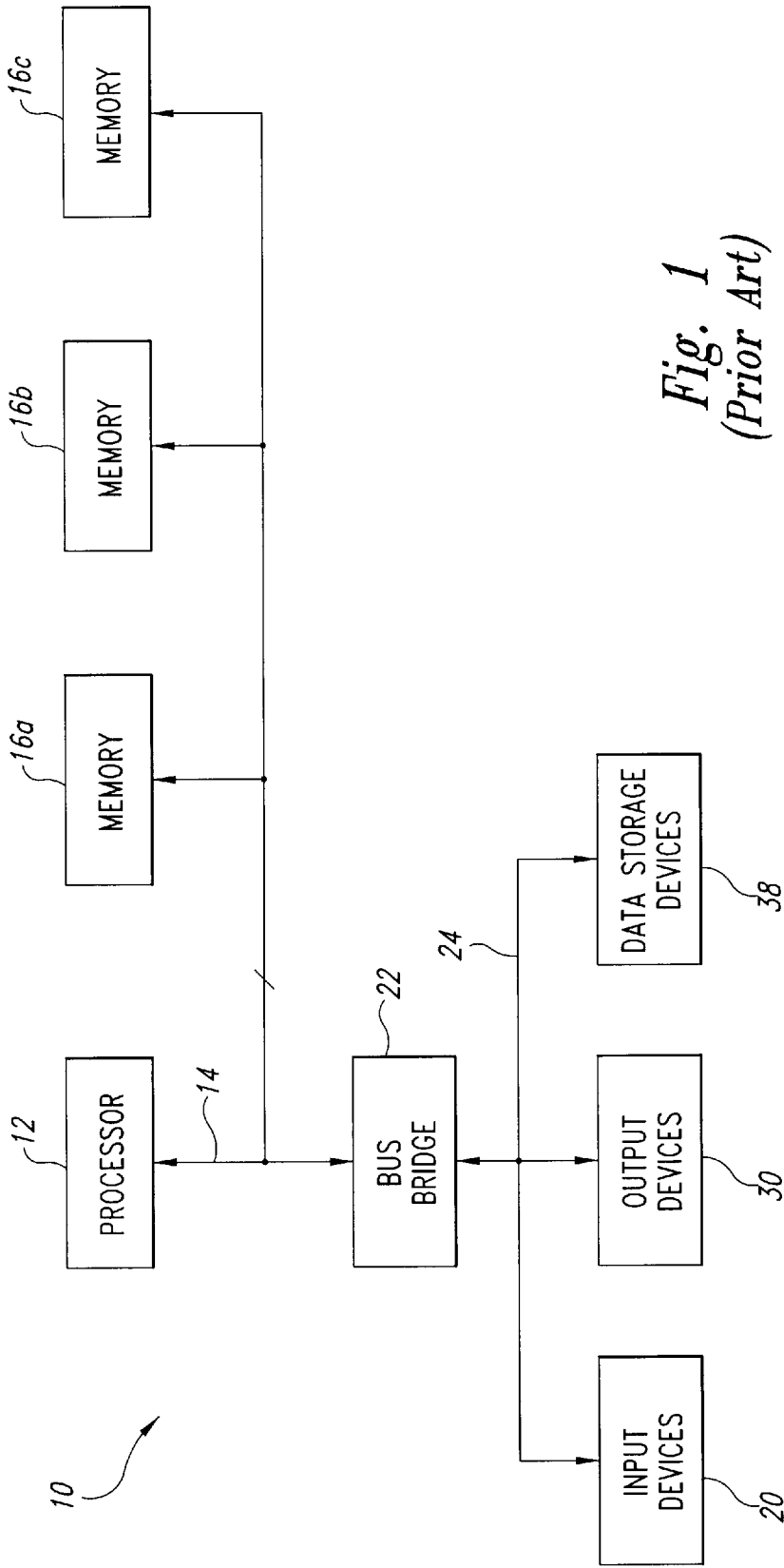


Fig. 1
(Prior Art)

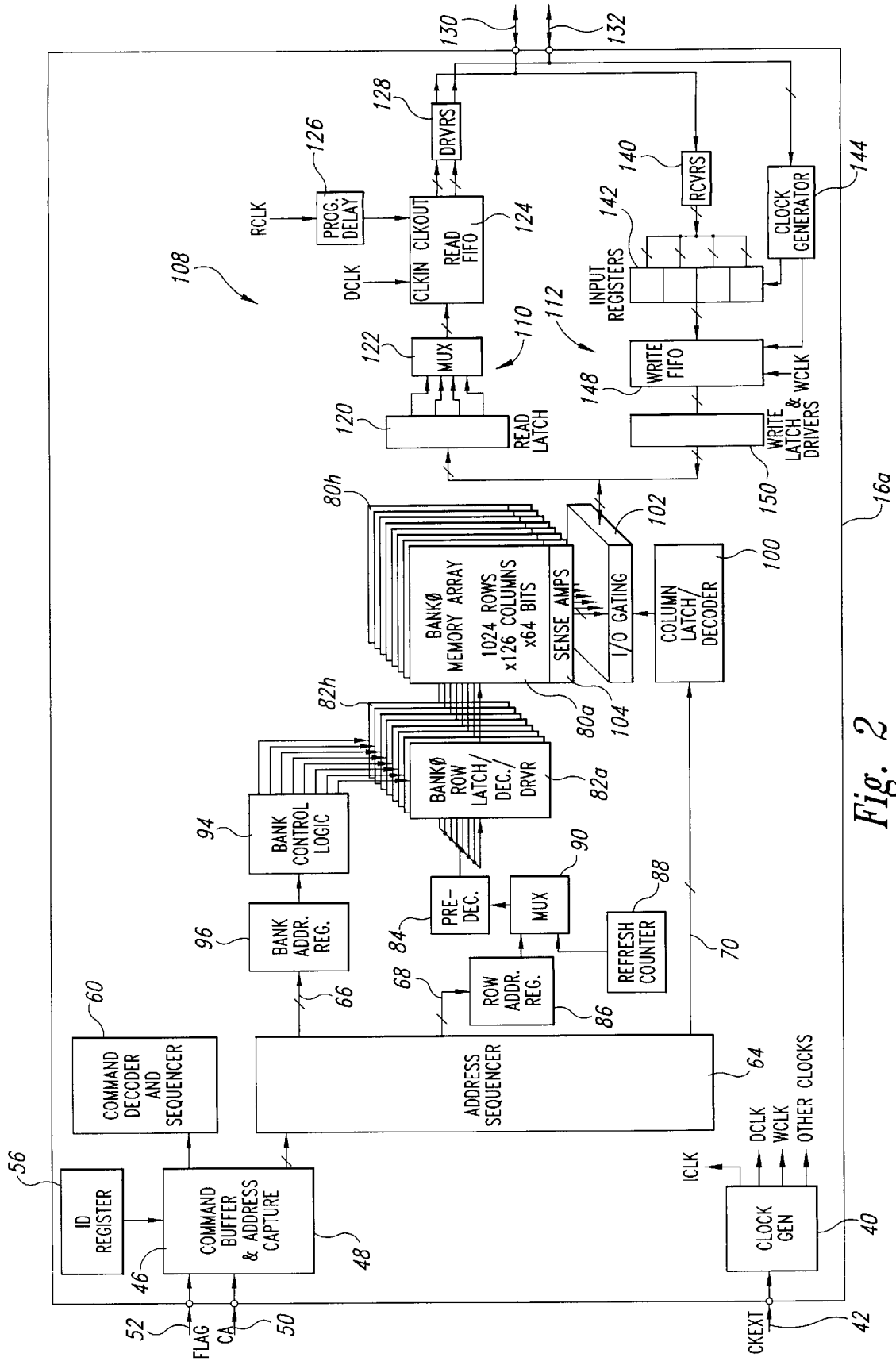


Fig. 2

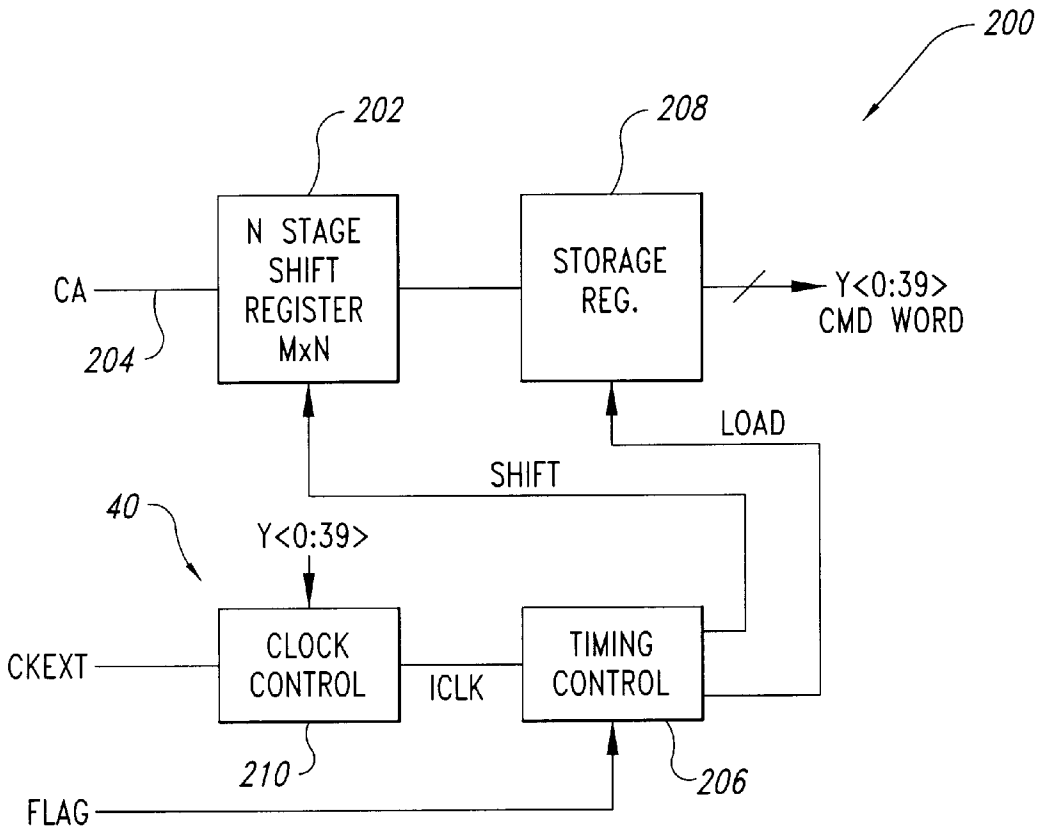


Fig. 3

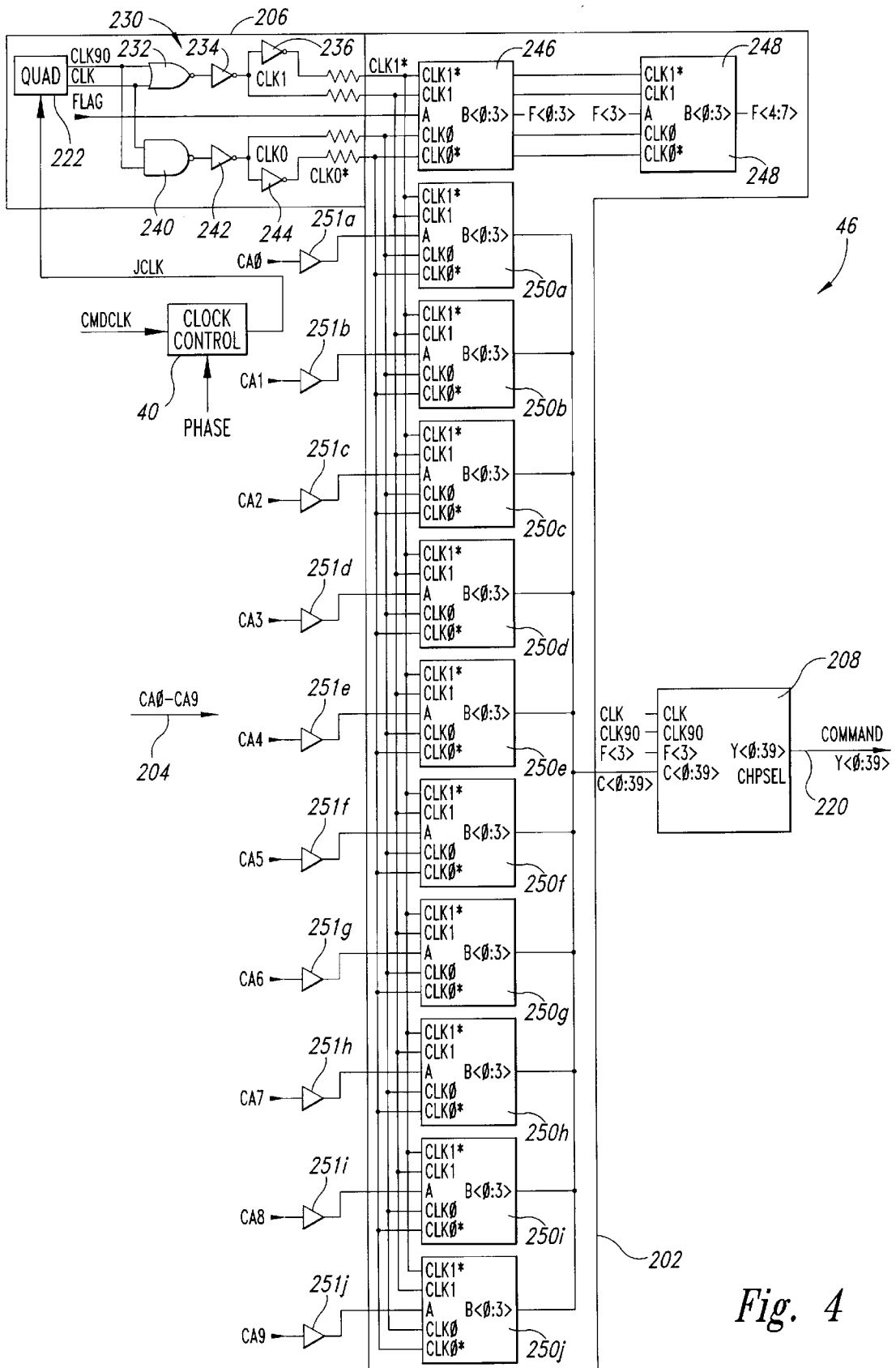


Fig. 4

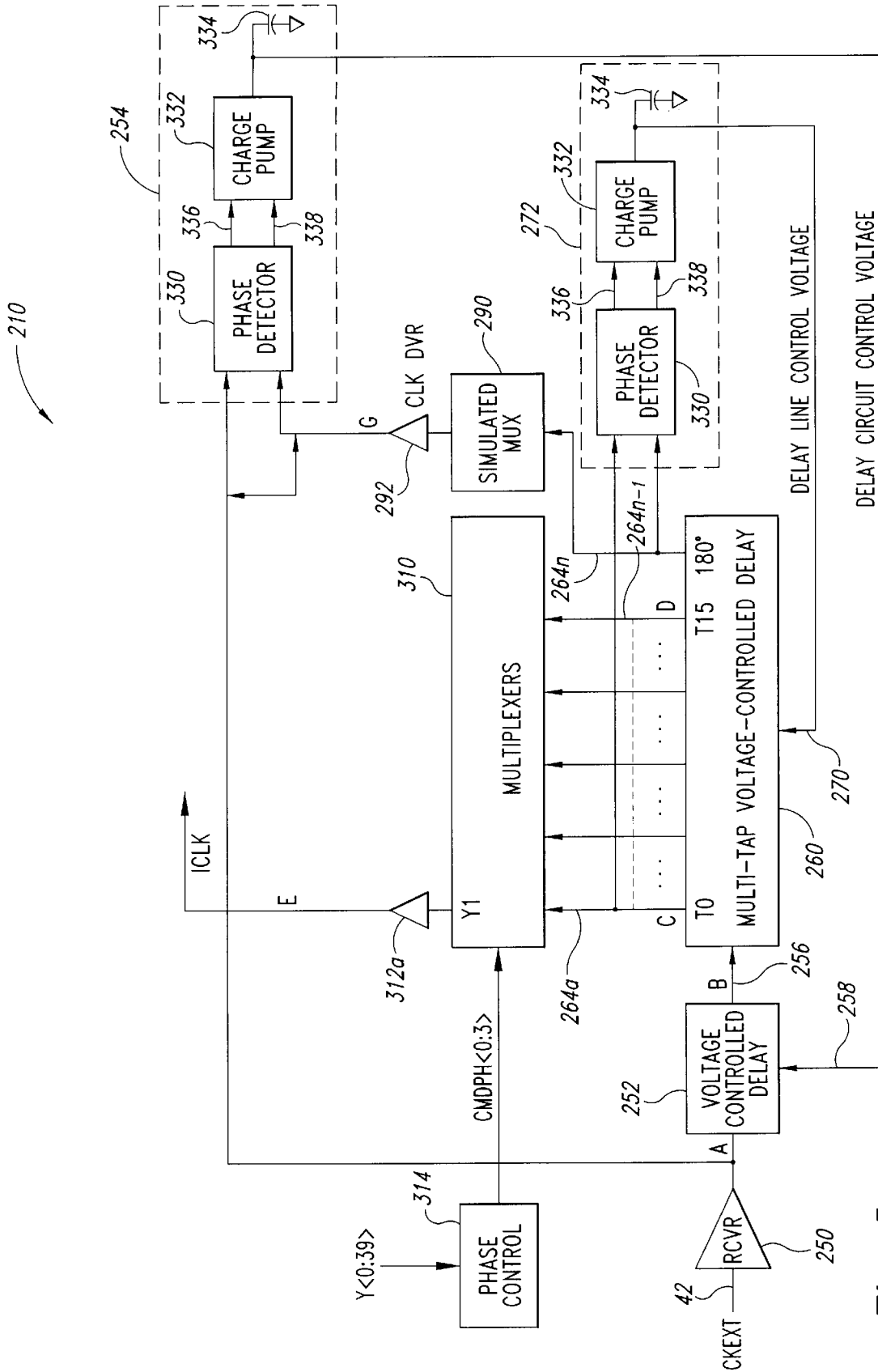


Fig. 5

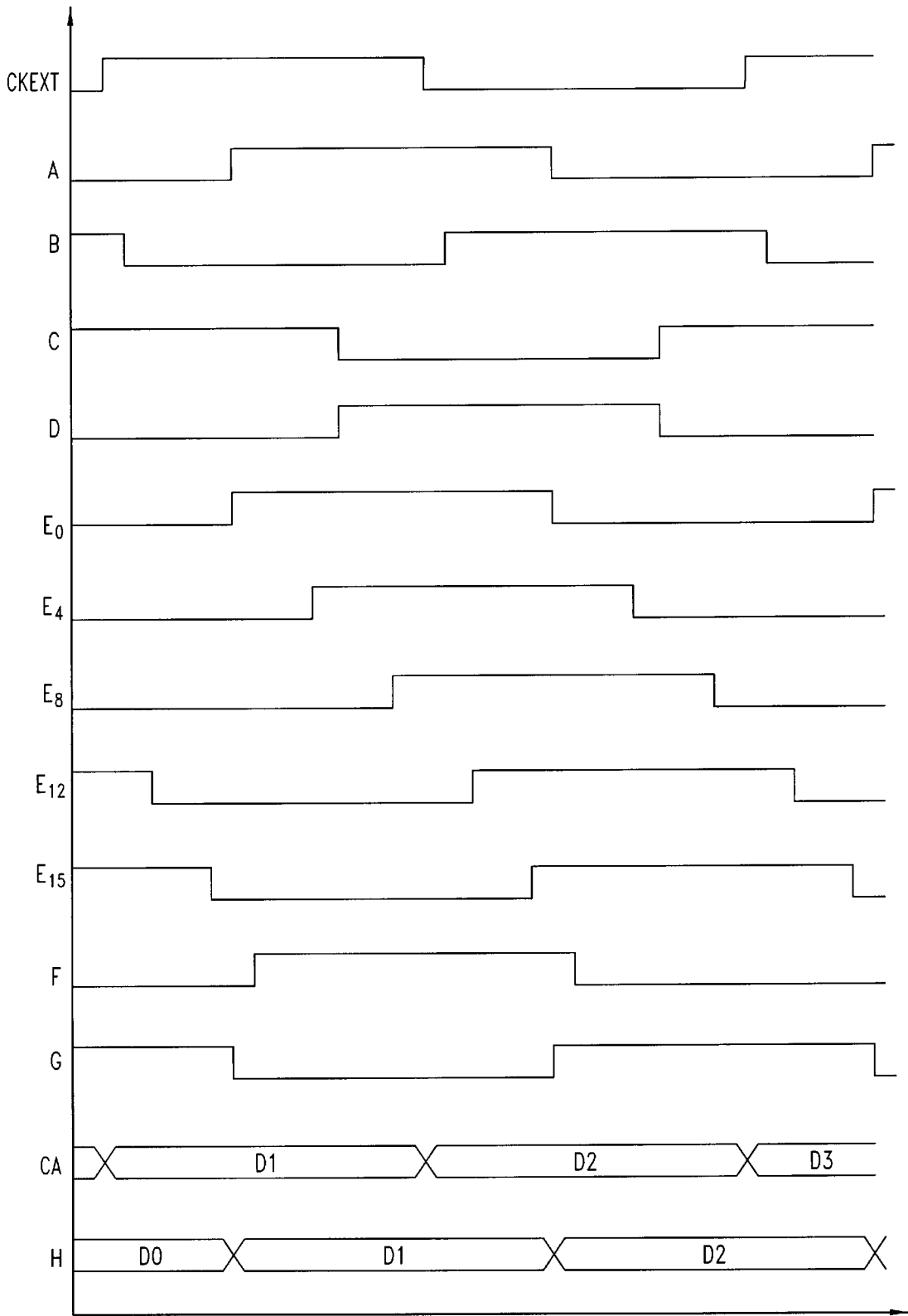


Fig. 6

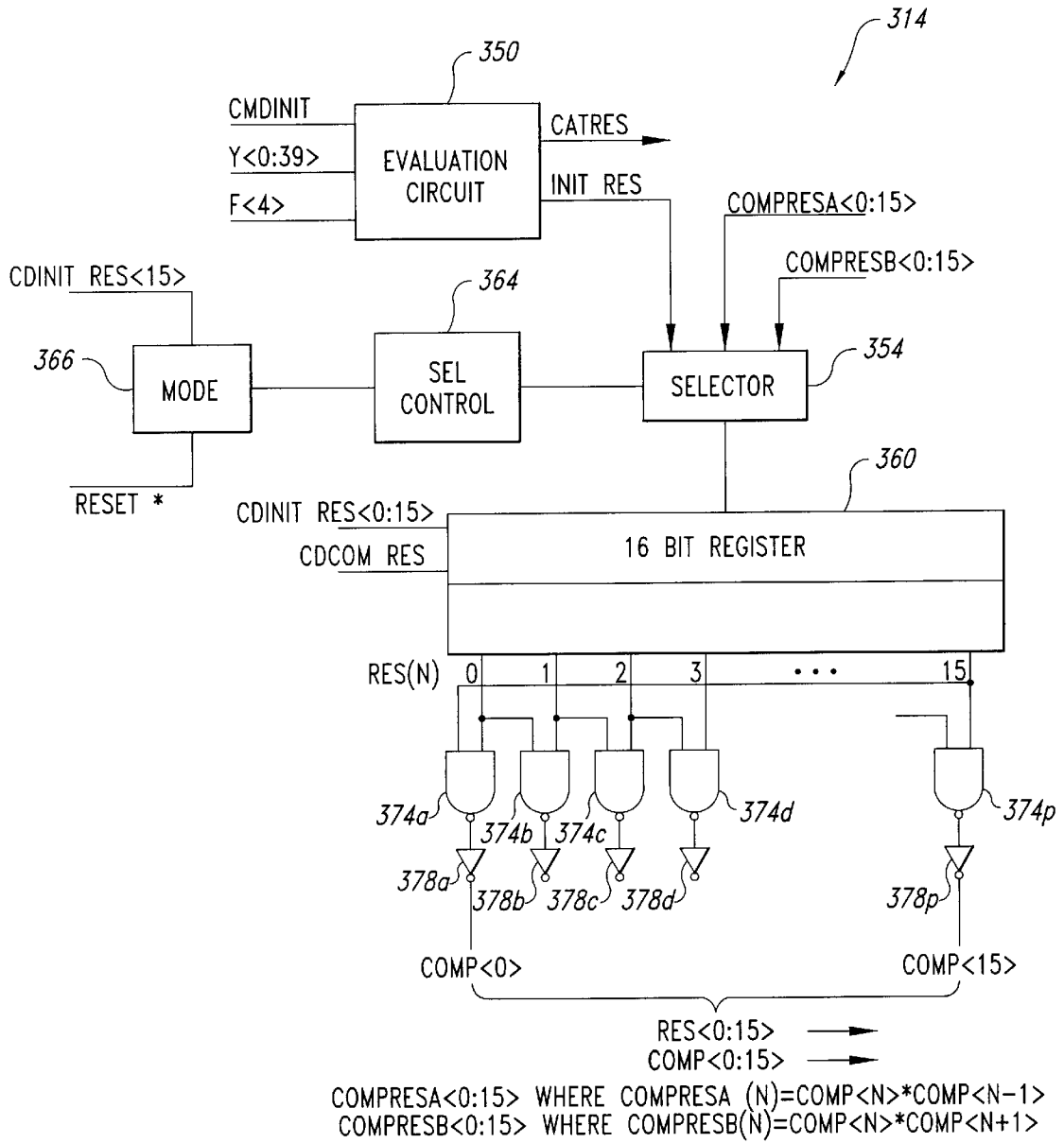


Fig. 7A

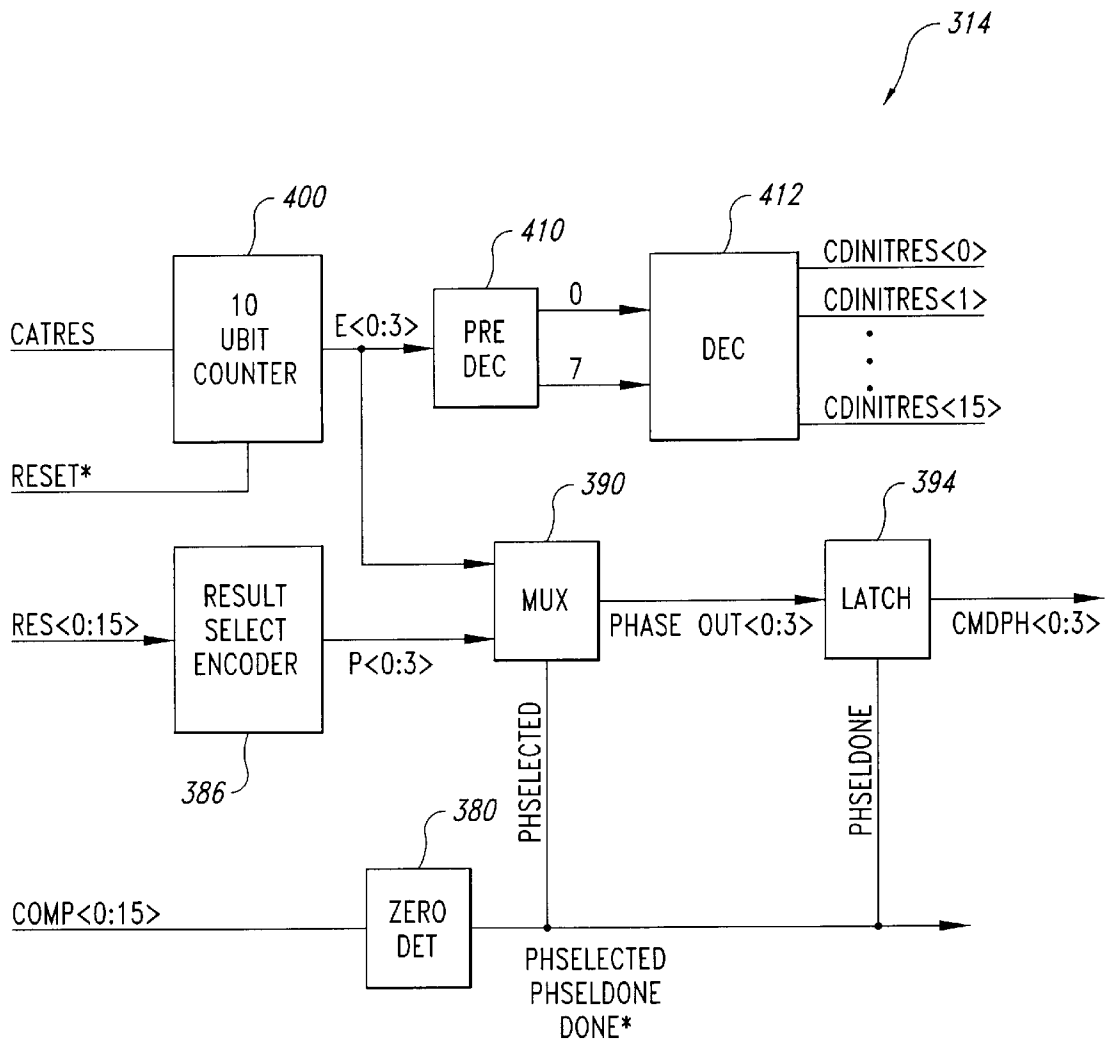


Fig. 7B

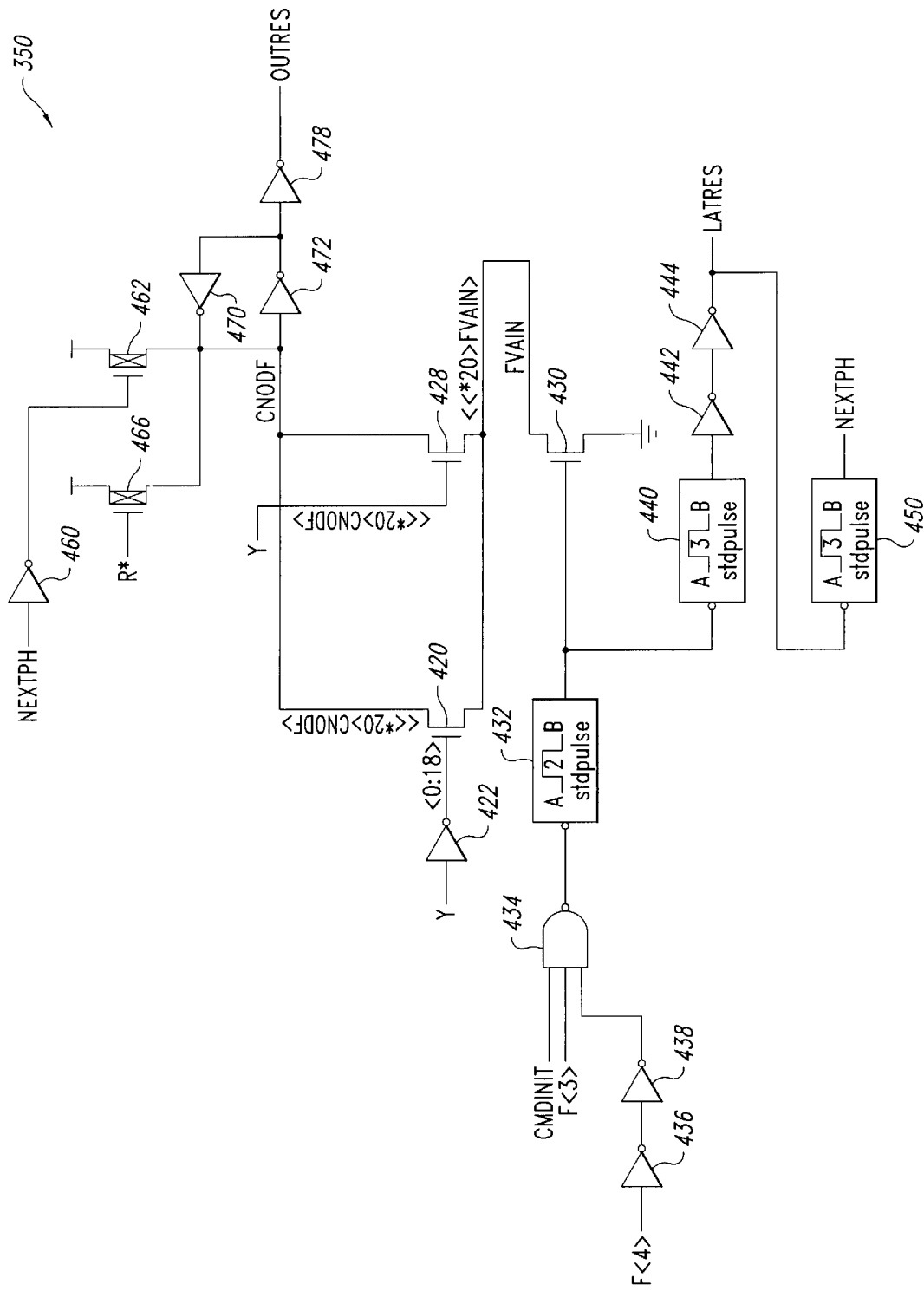


Fig. 8

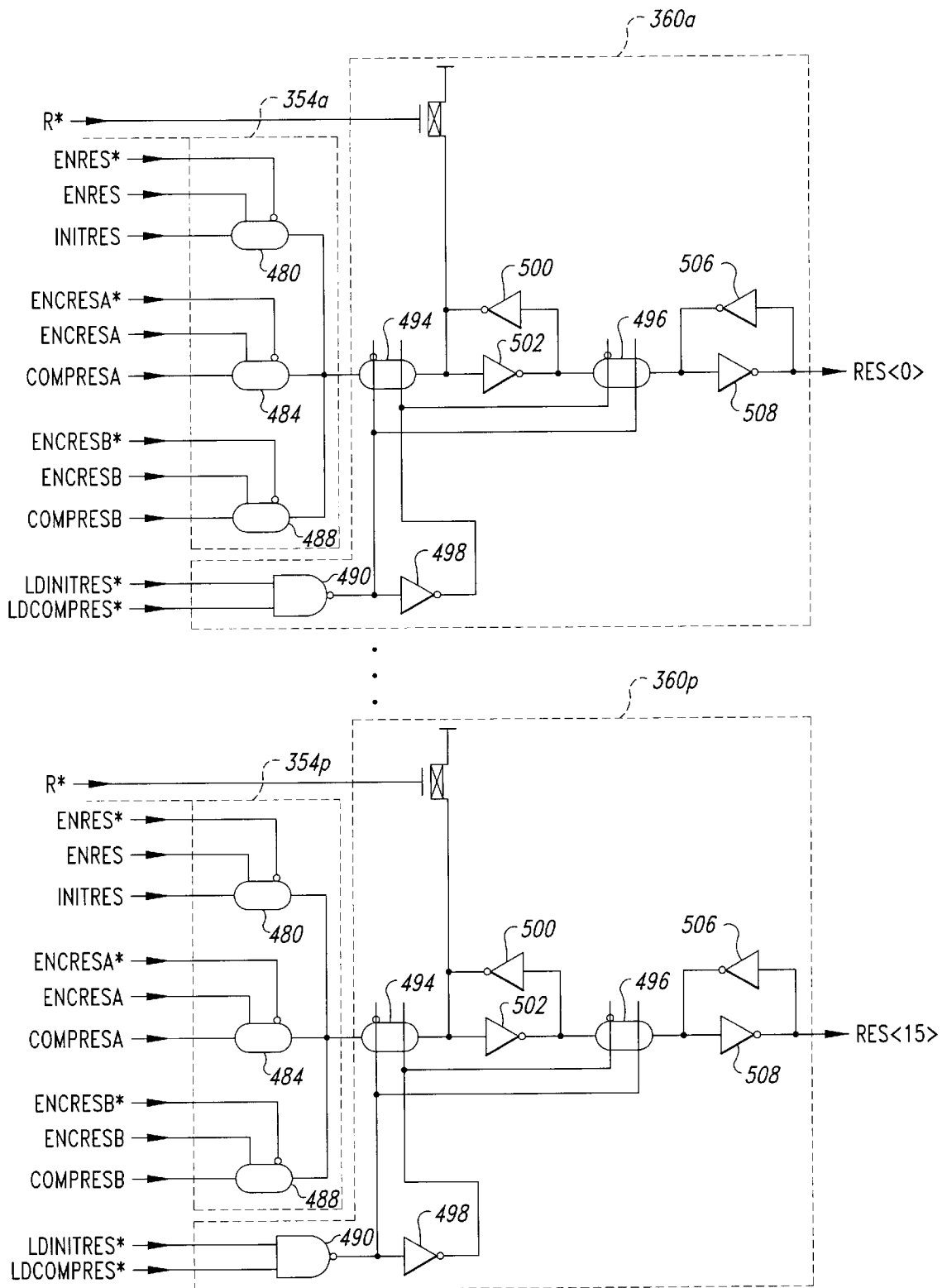


Fig. 9

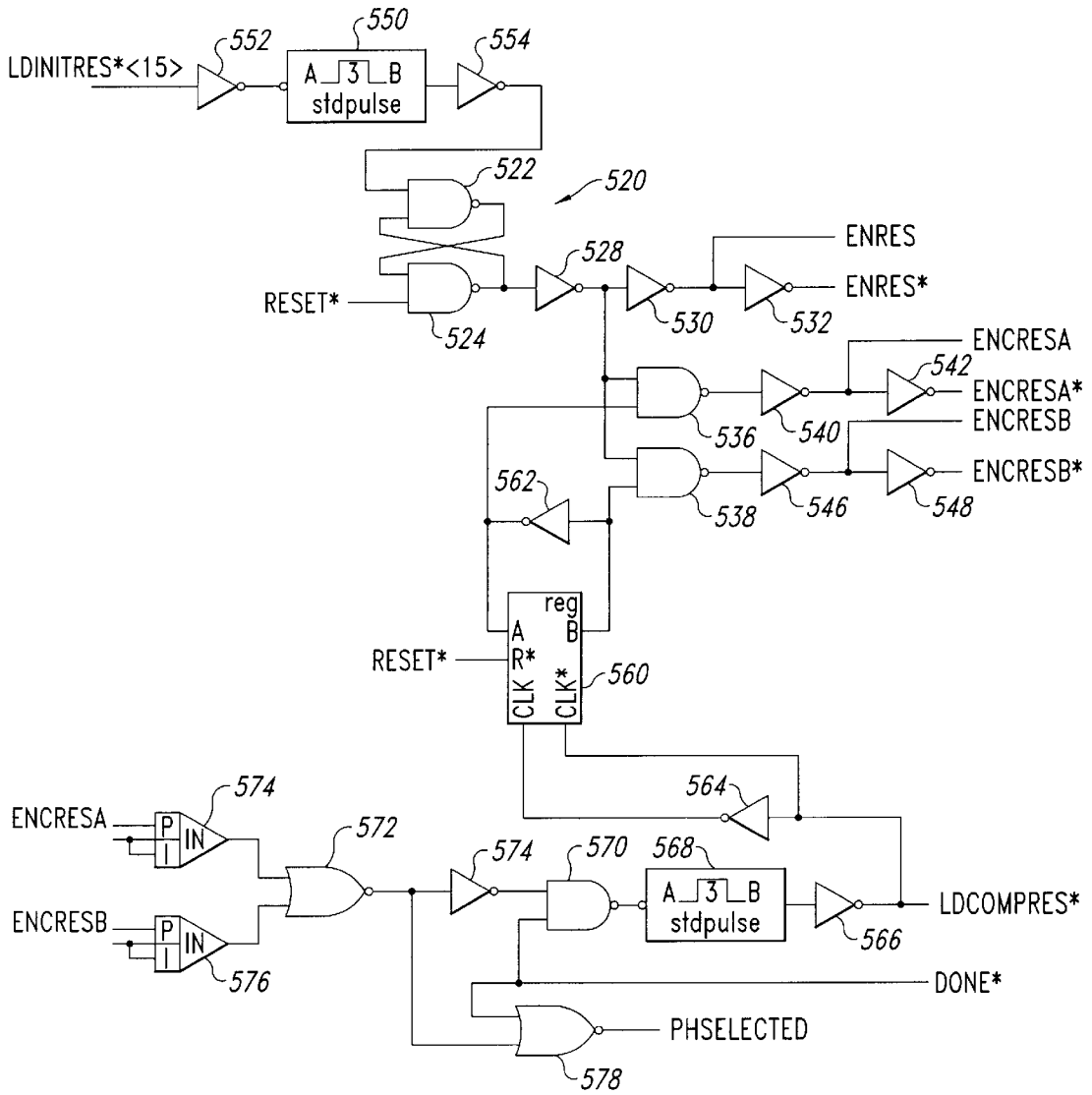


Fig. 10

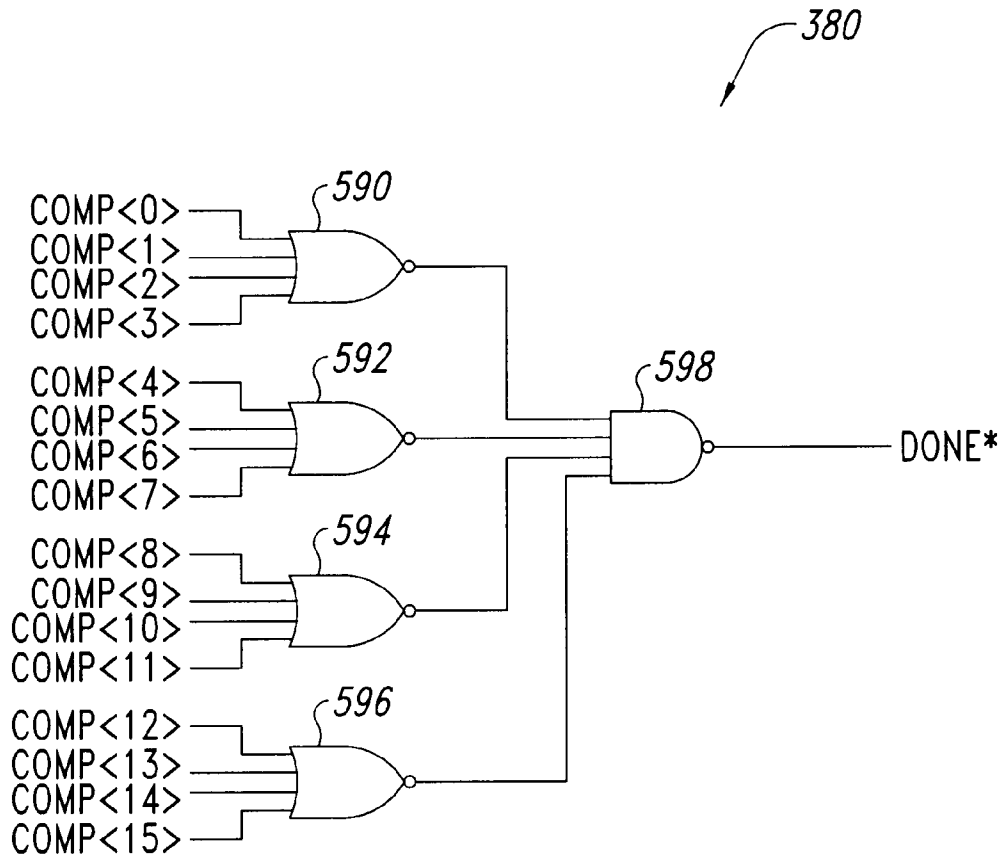


Fig. 11

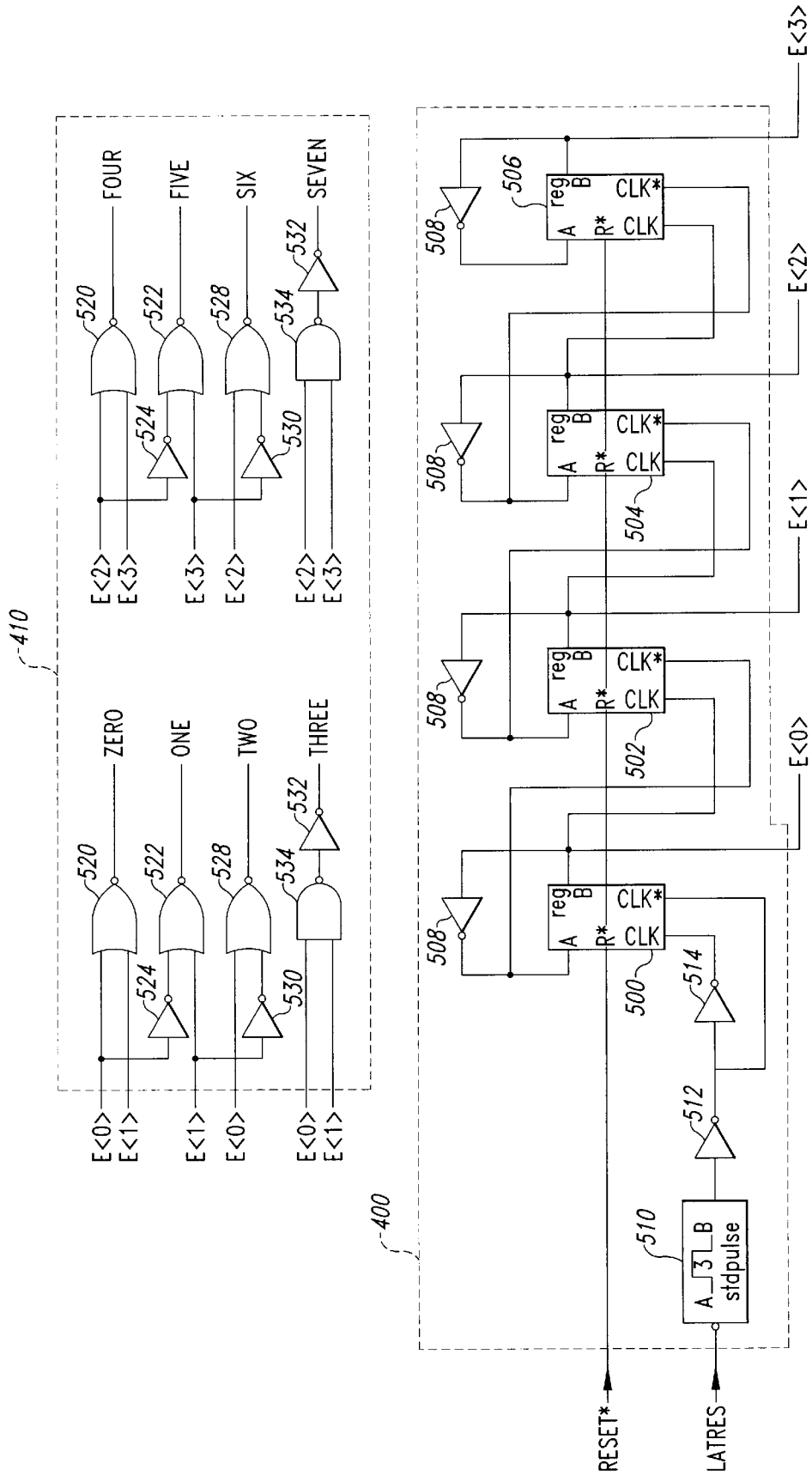


Fig. 12

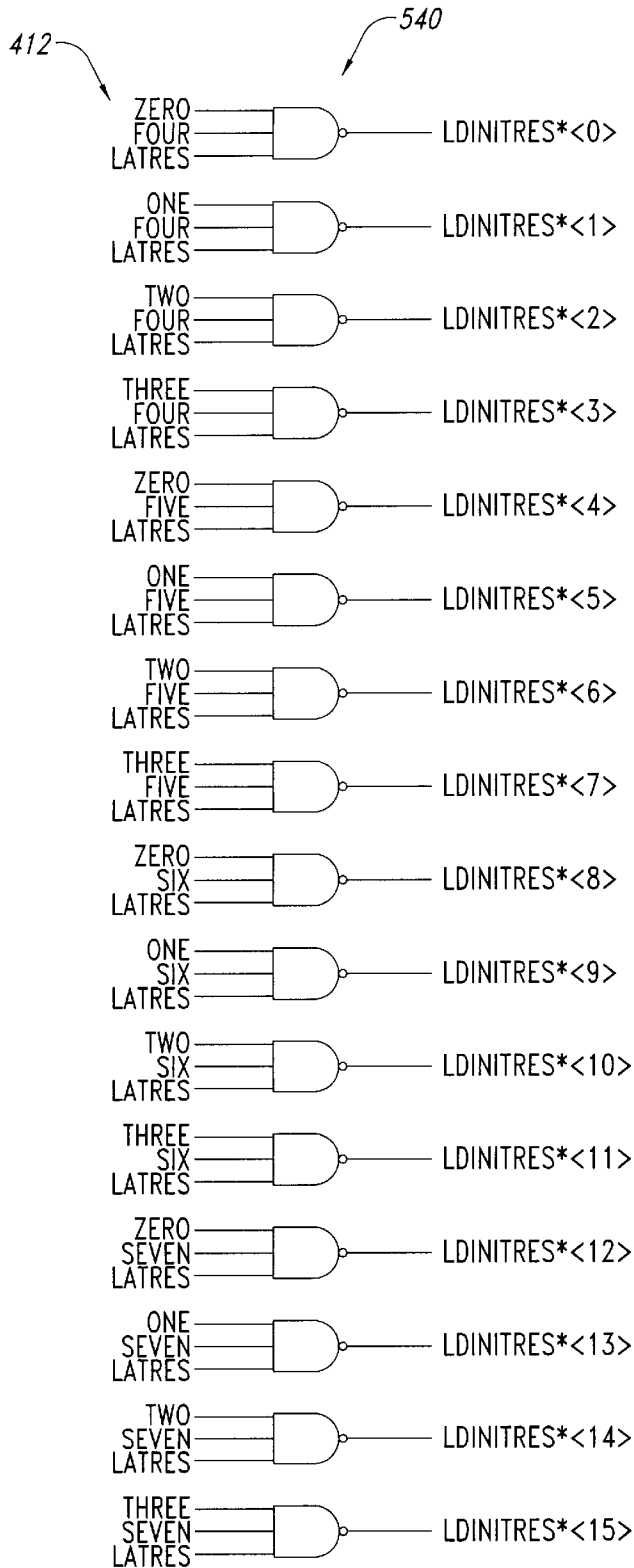


Fig. 13

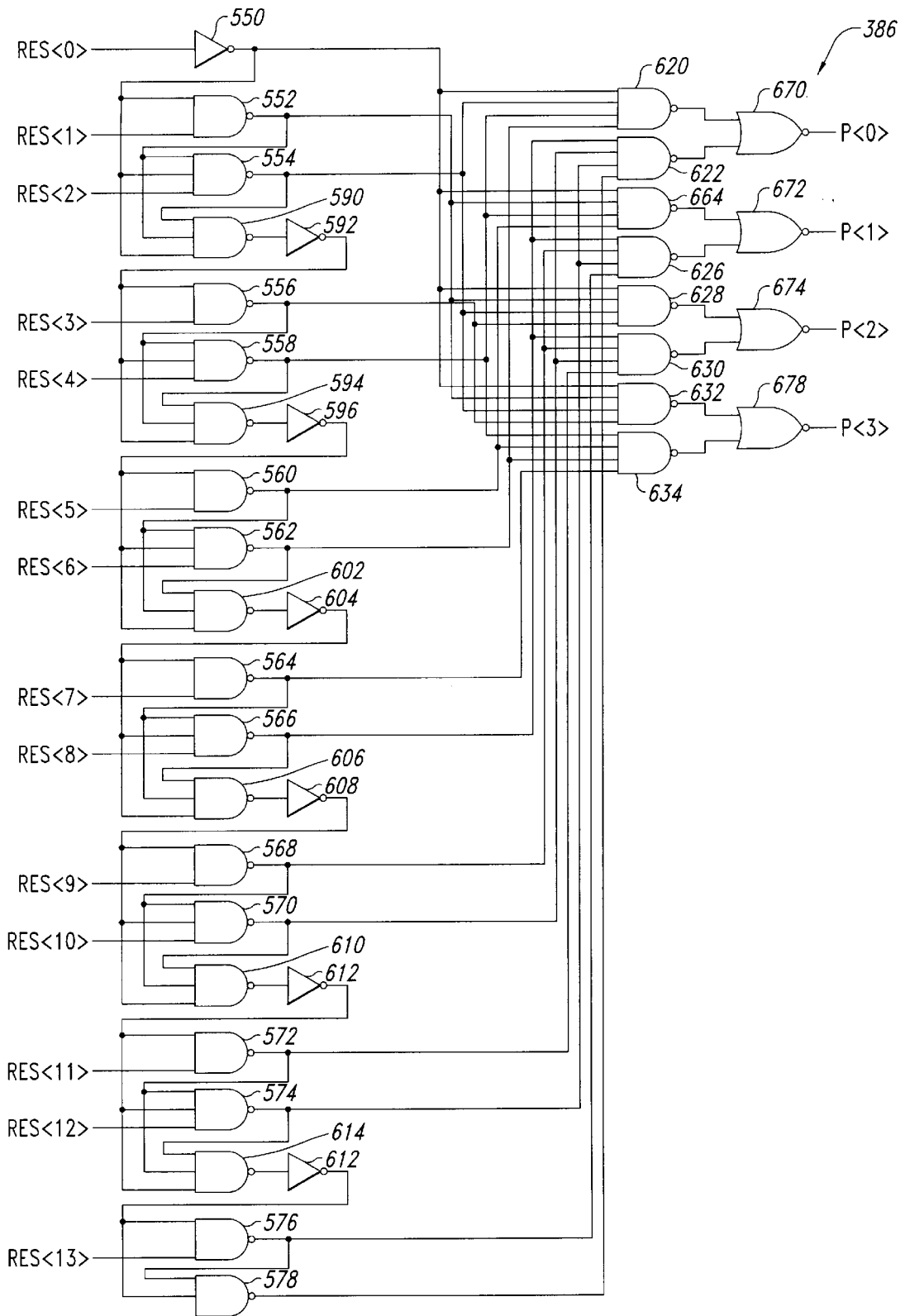


Fig. 14

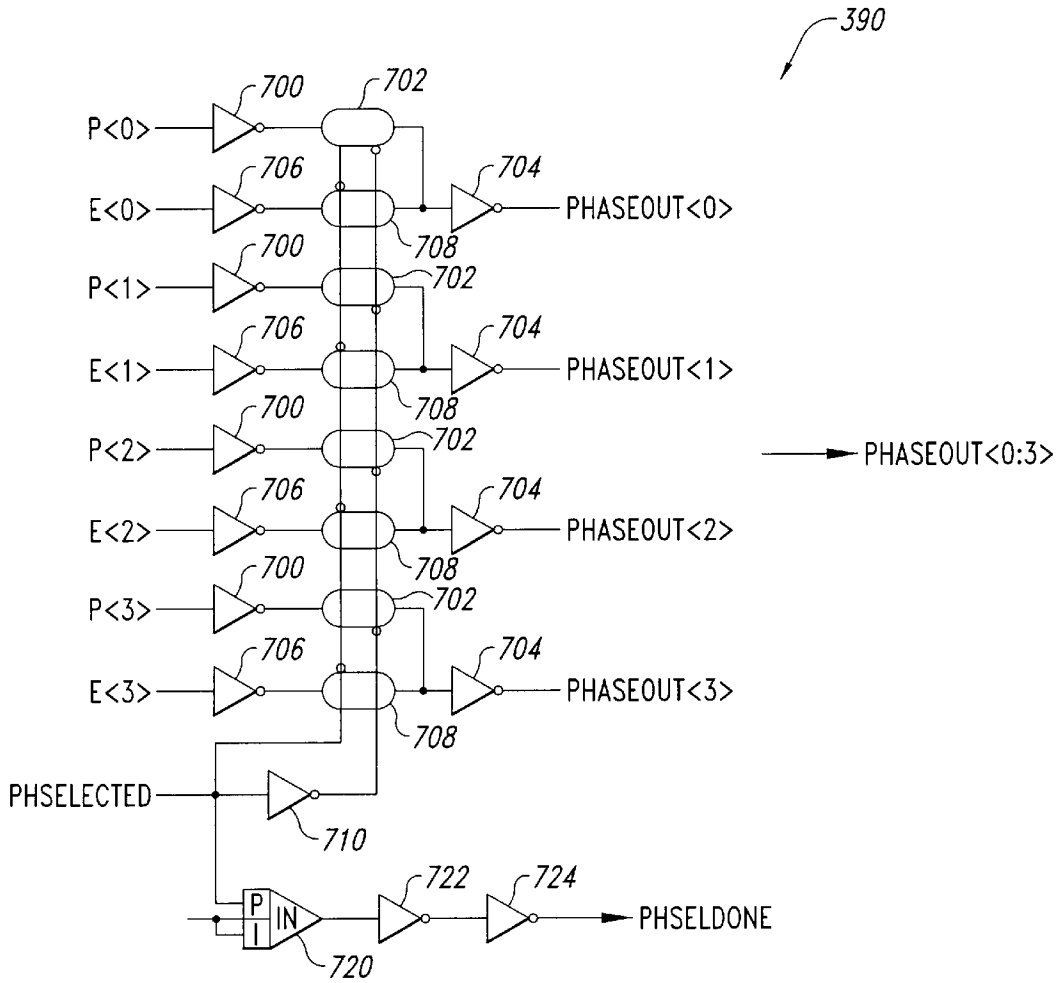


Fig. 15

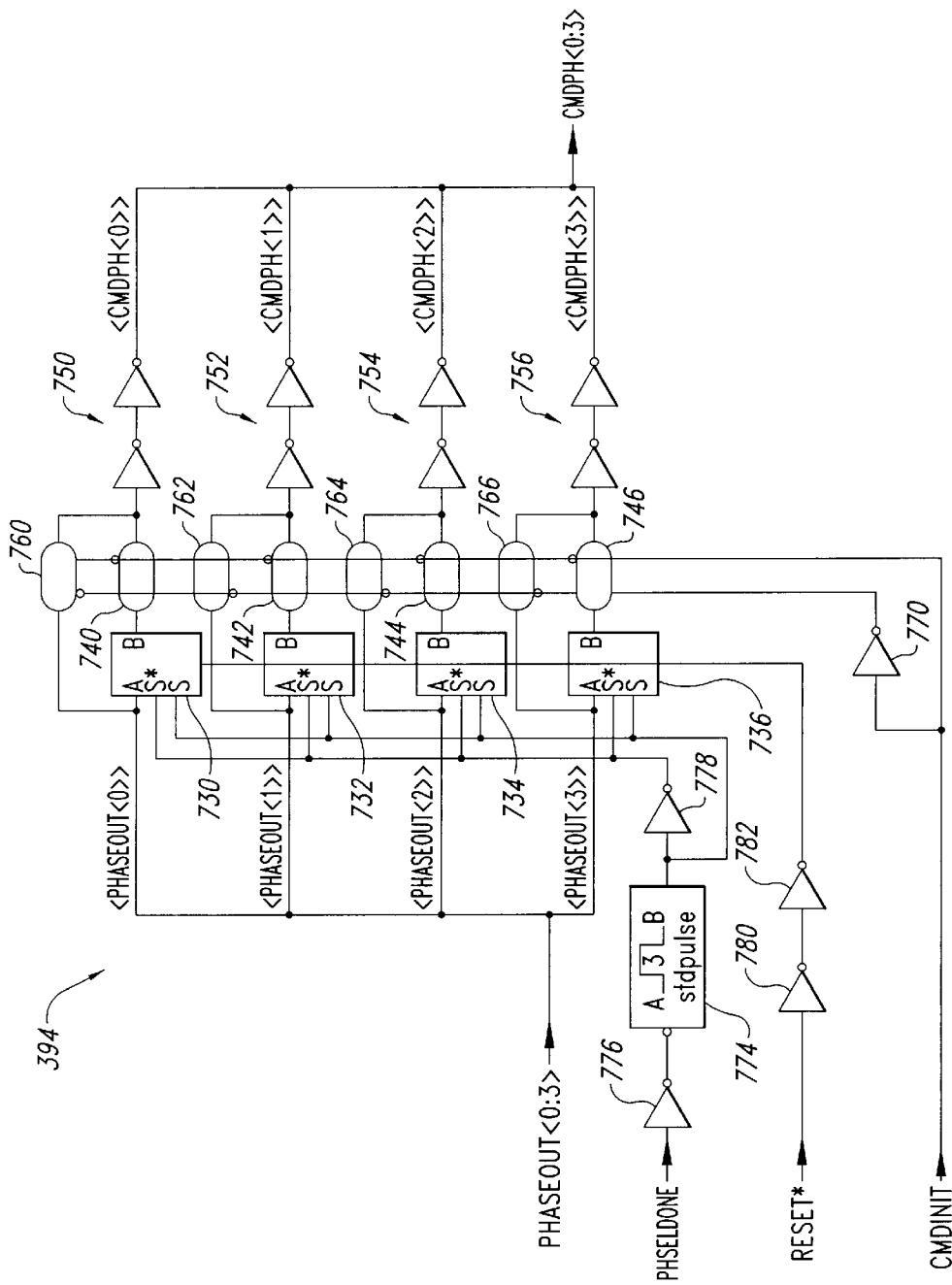


Fig. 16

**METHOD AND APPARATUS FOR
ADAPTIVELY ADJUSTING THE TIMING OF
A CLOCK SIGNAL USED TO LATCH
DIGITAL SIGNALS, AND MEMORY DEVICE
USING SAME**

TECHNICAL FIELD

The present invention relates to integrated circuit devices, and more particularly, to adjusting the timing of an internal clock signal derived from an external clock signal so that it can be used to latch an external digital signal at the optimum time.

BACKGROUND OF THE INVENTION

Conventional computer systems include a processor coupled to a variety of memory devices, including read-only memories ("ROMs") which traditionally store instructions for the processor, and a system memory to which the processor may write data and from which the processor may read data. The processor may also communicate with an external cache memory, which is generally a static random access memory ("SRAM"). The processor also communicates with input devices, output devices, and data storage devices.

Processors generally operate at a relatively high speed. Processors such as the Pentium® and Pentium Pro® microprocessors are currently available that operate at clock speeds of at least 200 MHz. However, the remaining components of the computer system, with the exception of SRAM cache memory, are not capable of operating at the speed of the processor. For this reason, the system memory devices, as well as the input devices, output devices, and data storage devices, are not coupled directly to the processor bus. Instead, the system memory devices are generally coupled to the processor bus through a memory controller, and the input devices, output devices, and data storage devices are coupled to the processor bus through a bus bridge. The memory controller allows the system memory devices to operate at a clock frequency that is substantially lower than the clock frequency of the processor. Similarly, the bus bridge allows the input devices, output devices, and data storage devices to operate at frequency that is a substantially lower than the clock frequency of the processor. Currently, for example, a processor having a 200 MHz clock frequency may be mounted on a mother board having a 66 MHz clock frequency for controlling the system memory devices and other components.

Access to system memory is a frequent operation for the processor. The time required for the processor, operating, for example, at 200 MHz, to read data from or write data to a system memory device operating at, for example, 66 MHz, greatly slows the rate at which the processor is able to accomplish its operations. Thus, much effort has been devoted to increasing the operating speed of system memory devices.

System memory devices are generally dynamic random access memories ("DRAMs"). Initially, DRAMs were asynchronous and thus did not operate at even the clock speed of the motherboard. In fact, access to asynchronous DRAMs often required that wait states be generated to halt the processor until the DRAM had completed a memory transfer. However, the operating speed of asynchronous DRAMs was successfully increased through such innovations as burst and page mode DRAMs, which did not require that an address be provided to the DRAM for each memory access. More recently, synchronous dynamic random access memo-

ries ("SDRAMs") have been developed to allow the pipelined transfer of data at the clock speed of the motherboard. However, even SDRAMs are typically incapable of operating at the clock speed of currently available processors. Thus, SDRAMs cannot be connected directly to the processor bus, but instead must interface with the processor bus through a memory controller, bus bridge, or similar device. The disparity between the operating speed of the processor and the operating speed of SDRAMs continues to limit the speed at which processors may complete operations requiring access to system memory.

A solution to this operating speed disparity has been proposed in the form of a computer architecture known as "SyncLink." In the SyncLink architecture, the system memory may be coupled to the processor directly through the processor bus. Rather than requiring that separate address and control signals be provided to the system memory, SyncLink memory devices receive command packets that include both control and address information. The SyncLink memory device then outputs or receives data on a data bus that is coupled directly to the data bus portion of the processor bus.

An example of a computer system **10** using the SyncLink architecture is shown in FIG. **1**. The computer system **10** includes a processor **12** having a processor bus **14** coupled to three packetized dynamic random access memory or SyncLink DRAMs ("SLDRAM") devices **16a-c**. The computer system **10** also includes one or more input devices **20**, such as a keypad or a mouse, coupled to the processor **12** through a bus bridge **22** and an expansion bus **24**, such as an industry standard architecture ("ISA") bus or a Peripheral component interconnect ("PCI") bus. The input devices **20** allow an operator or an electronic device to input data to the computer system **10**. One or more output devices **30** are coupled to the processor **12** to display or otherwise output data generated by the processor **12**. The output devices **30** are coupled to the processor **12** through the expansion bus **24**, bus bridge **22** and processor bus **14**. Examples of output devices **24** include printers and a video display units. One or more data storage devices **38** are coupled to the processor **12** through the processor bus **14**, bus bridge **22**, and expansion bus **24** to store data in or retrieve data from storage media (not shown). Examples of storage devices **38** and storage media include fixed disk drives floppy disk drives, tape cassettes and compact-disk read-only memory drives.

In operation, the processor **12** communicates with the memory devices **16a-c** via the processor bus **14** by sending the memory devices **16a-c** command packets that contain both control and address information. Data is coupled between the processor **12** and the memory devices **16a-c**, through a data bus portion of the processor bus **14**. Although all the memory devices **16a-c** are coupled to the same conductors of the processor bus **14**, only one memory device **16a-c** at a time reads or writes data, thus avoiding bus contention on the processor bus **14**. Bus contention is avoided by each of the memory devices **16a-c** on the bus bridge **22** having a unique identifier, and the command packet contains an identifying code that selects only one of these components.

The computer system **10** also includes a number of other components and signal lines which have been omitted from FIG. **1** in the interests of brevity. For example, as explained below, the memory devices **16a-c** also receive an external clock signal CKEXT to provide internal timing signals, a data clock signal DCLK clocking data into or out of the memory device **16**, and a FLAG signal signifying the start of a command packet.

One of the memory devices **16a** is shown in block diagram form in FIG. 2. The memory device **16a** includes a clock generator circuit **40** that receives a master clock signal CKEXT and generates an internal clock signal CKINT and a large number of other clock and timing signals to control the timing of various operations in the memory device **16**. The memory device **16** also includes a command buffer **46** and an address capture circuit **48** which receive an internal clock signal CKINT, a command packet CA0-CA9 on a 10-bit command bus **50**, and a FLAG signal on line **52**. The memory controller (not shown) or other device normally transmits the command packet CA0-CA9 to the memory device **16a** in synchronism with the external clock signal CKEXT. As explained above, the command packet contains control and address information for each memory transfer, and the FLAG signal identifies the start of a command packet which may include more than one 10-bit packet word. In fact, a command packet is generally in the form of a sequence of 10-bit packet words on the 10-bit command bus **50**. The command buffer **46** receives the command packet from the bus **50**, and compares at least a portion of the command packet to identifying data from an ID register **56** to determine if the command packet is directed to the memory device **16a** or some other memory device **16b, c**. If the command buffer **46** determines that the command packet is directed to the memory device **16a**, it then provides a command word to a command decoder and sequencer **60**. The command decoder and sequencer **60** generates a large number of internal control signals to control the operation of the memory device **16a** during a memory transfer.

The address capture circuit **48** also receives the command words from the command bus **50** and outputs a 20-bit address corresponding to the address information in the command packet. The address is provided to an address sequencer **64** which generates a corresponding 3-bit bank address on bus **66**, a 10-bit row address on bus **68**, and a 7-bit column address on bus **70**. The column address and row address are processed by column and row address paths **73, 75** as will be described below.

One of the problems of conventional DRAMs is their relatively low speed resulting from the time required to precharge and equilibrate circuitry in the DRAM array. The packetized DRAM **16a** shown in FIG. 2 largely avoids this problem by using a plurality of memory banks **80**, in this case eight memory banks **80a-h**. After a memory read from one bank **80a**, the bank **80a** can be precharged while the remaining banks **80b-h** are being accessed. Each of the memory banks **80a-h** receive a row address from a respective row latch/decoder/driver **82a-h**. All of the row latch/decoder/drivers **82a-h** receive the same row address from a predecoder **84** which, in turn, receives a row address from either a row address register **86**, redundant row circuit **87**, or a refresh counter **88** as determined by a multiplexer **90**. However, only one of the row latch/decoder/drivers **82a-h** is active at any one time as determined by bank control logic **94** as a function of a bank address from a bank address register **96**.

The column address on bus **70** is applied through a column address path **75** to a redundant column circuit **71** that determines if the column address corresponds to a defective address. The redundant column circuit **71** outputs either the column address or a redundant column address to a column latch/decoder **100** which supplies I/O gating signals to an I/O gating circuit **102**. The I/O gating circuit **102** interfaces with columns of the memory banks **80a-h** through sense amplifiers **104**. Data is coupled to or from the memory banks **80a-h** through the sense amplifiers **104** and I/O gating

circuit **102** to a data path subsystem **108** which includes a read data path **110** and a write data path **112**. The read data path **110** includes a bank of DC sense amplifiers **103** and a read latch **120** that amplify and store data from the I/O gating circuit **102**. In the memory device **16a** shown in FIG. 2, 64 bits of data are stored in the read latch **120**. The read latch then provides four 16-bit data words to an output multiplexer **122** that sequentially supplies each of the 16-bit data words to a read FIFO buffer **124**. Successive 16-bit data words are clocked through the read FIFO buffer **124** by a clock signal RCLK generated from the internal clock CKINT by a programmable delay circuit **126**. The read FIFO buffer **124** sequentially applies the 16-bit words to a driver circuit **128** which, in turn, applies the 16-bit data words to a data bus **130** forming part of the processor bus **14**.

The write data path **112** includes a receiver buffer **140** coupled to the data bus **130**. The receiver buffer **140** sequentially applies 16-bit words from the data bus **130** to four input registers **142**, each of which is selectively enabled by a signal from a clock generator circuit **144** responsive to the data clock DCLK applied to the memory device **16a** on line **132**. As with the external clock signal CKEXT and command packet CA0-CA9, the memory controller or other device (not shown) normally transmits the data to the memory device **16a** in synchronism with the data clock signal DCLK. Thus, the input registers **142** sequentially store four 16-bit data words and combine them into one 64-bit data word applied to a write FIFO buffer **148**. The write FIFO buffer **148** is clocked by a signal from the clock generator **144** and an internal write clock WCLK to sequentially apply 64-bit write data to a write latch and driver **150**. The write latch and driver **150** applies the 64-bit write data to one of the memory banks **80a-h** through the I/O gating circuit **102** and the sense amplifiers **104**.

As mentioned above, an important goal of the SyncLink architecture is to allow data transfer between a processor and a memory device to occur at a significantly faster rate. However, as the rate of data transfer increases, it becomes more difficult to maintain synchronization between signals transmitted to the memory device **16a**. For example, as mentioned above, the command packet CA0-CA9 is normally transmitted to the memory device **16a** in synchronism with the external clock signal CKEXT, and the data is normally transmitted to the memory device **16a** in synchronism with the data clock signal DCLK. However, because of unequal signal delays and other factors, the command packet CA0-CA9 may not arrive at the memory device **16a** in synchronism with the external clock signal CKEXT, and the data may not arrive at the memory device **16a** in synchronism with the data clock signal DCLK. Even if these signals are actually coupled to the memory device **16a** in synchronism with each other, they may lose synchronism once they are coupled to circuits within the memory device. For example, internal signals require time to propagate to various circuitry in the memory device **16a**. Difference in length of the signal routing can cause differences in the times at which signals reach the circuitry. Differences in capacitive loading of signal lines can also cause differences in the times at which signals reach the circuitry. These differences in arrival times can become significant at high speeds of operation and eventually limit the operating speed of memory devices.

As mentioned above, the above-described problems are exacerbated as timing tolerances become more severe with higher data transfer rates. For example, if the internal clock CKINT derived from the external clock CKEXT does not latch the command packet CA0-CA9 at the proper time,

errors in the operation of the memory device may result. Similarly, if the data clock DCLK does not latch the data applied to the memory device at the proper time, data errors may result.

Unfortunately, there has heretofore been no suitable means for ensuring that digital signals, such as the command packets CA0-CA9 and digital signals, are latched in memory devices, such as the packetized DARM shown in FIG. 2, at the proper time at very high data transfer rates.

Although the foregoing discussion is directed to the need for faster command buffers in packetized DRAMs, similar problems exist in other memory devices, such as asynchronous DRAMs and synchronous DRAMs, which must process control and other signals at a high rate of speed.

SUMMARY OF THE INVENTION

Although the inventive system for adaptively adjusting the timing of an internal clock signal may be used in any integrated circuit, it is particularly well adapted for use in a memory device, such as a packetized dynamic random access memory device, to control the latching of commands applied to the memory device. The invention may be embodied in a variety of systems that adaptively adjust the phase of an internal clock signal relative to an external clock signal. The systems may operate by repetitively receiving a digital signal each of which is latched responsive to respective phases of the internal clock signal. The latched digital signals are then examined to determine if they were correspond to the received digital signals. A phase of the internal clock signal is then selected from within the range of phases of the internal clock signal that accurately latched the respective digital signals. The system preferably includes a clock generator circuit that generates the internal clock signal. The internal clock signal has a phase relative to the external clock signal determined by a phase command signal. The internal clock signal triggers a latch circuit, such as a shift register. The latch circuit is coupled to one of the input terminals of the integrated circuit so that the latch stores an input signal applied to the input terminal responsive to a transition of the internal clock signal. The timing control system also includes a load control circuit generating a plurality of phase command signals responsive to storing a plurality of respective input signals in the latch. Each of the phase command signals corresponds to different respective phases of the internal clock signal. An evaluation circuit coupled to the latch receives a plurality of latched signals and determines if each of the latched signals was accurately captured by the latch. The evaluation circuit generates a plurality of respective results signals indicative of whether each of the latched signals was accurately captured by the latch. The results signals are then stored in a register that is coupled to the evaluation circuit and the load control circuit. An analysis circuit coupled to the register examines the results signals stored in the register and, based on the examination of the stored results signals, generates and continuously applies to the clock generator circuit the phase command signal.

BRIEF DESCRIPTION OF THE DRAWINGS

FIG. 1 is a block diagram of a conventional computer system using a plurality of SyncLink packetized memory devices.

FIG. 2 is a block diagram of a conventional packetized DRAM used in the computer system of FIG. 1.

FIG. 3 is a block diagram of a preferred embodiment of a portion of a command buffer and clock generator circuit in

accordance with the invention that is usable in the packetized DRAM of FIG. 2.

FIG. 4 is a more detailed block diagram of the portion of the command buffer and clock generator circuit shown in FIG. 3.

FIG. 5 is a logic diagram and block diagram of the clock control circuit used in the clock generator circuit of FIG. 4.

FIG. 6 is a timing diagram showing various signals present in the clock control circuit of FIG. 5.

FIGS. 7A and 7B are a block diagram of one embodiment of a phase control circuit used in the clock control circuit of FIG. 5.

FIG. 8 is a logic diagram and schematic of an evaluation circuit used in the phase control circuit of FIGS. 7A and 7B.

FIG. 9 is a logic diagram and schematic of a register and a signal selector used in the phase control circuit of FIGS. 7A and 7B.

FIG. 10 is a logic diagram of a mode circuit and selector control circuit used in the phase control circuit of FIGS. 7A and 7B.

FIG. 11 is a logic diagram of a zero detector circuit used in the phase control circuit of FIGS. 7A and 7B.

FIG. 12 is a logic diagram of a counter and a predecoder circuit used in the phase control circuit of FIGS. 7A and 7B.

FIG. 13 is a logic diagram of a decoder circuit used in the phase control circuit of FIGS. 7A and 7B.

FIG. 14 is a logic diagram and schematic of a results selector encoder used in the phase control circuit of FIGS. 7A and 7B.

FIG. 15 is a logic diagram of a multiplexer circuit used in the phase control circuit of FIGS. 7A and 7B.

FIG. 16 is a logic diagram of a latch circuit used in the phase control circuit of FIGS. 7A and 7B.

DETAILED DESCRIPTION OF THE INVENTION

One embodiment of a command buffer and clock control circuit 200 in accordance with the invention is illustrated in FIG. 3. The command buffer and clock control circuit 200 can be used in place of the command buffer 46 and clock generator 40 in FIG. 2, and the resulting memory device may be used in the computer system shown in FIG. 1. With reference to FIG. 3, a command packet CA consisting of a plurality of packet words is applied to a shift register 202 via a command bus 204. The width of the bus 204 corresponds to the size of the shift register 202, and the number of packet words in the command packet corresponds to the number of stages of the shift register 202. In the embodiment shown in FIG. 3, the shift register 202 has four stages, each of which is 10 bits wide. Thus, the shift register 202 sequentially receives four 10-bit packet words CA<0:9>. Each of the four packet words is shifted into the shift register 202, and from one shift register stage to the next, responsive to each of a plurality of SHIFT pulses.

Coincident with the start of a four packet word command packet, a FLAG signal is applied to a timing control circuit 206. The FLAG signal enables the timing control circuit 206 to generate the SHIFT pulses responsive to the internal clock signal ICLK. After four packet words have been shifted into the shift register 202, the control circuit 206 generates a LOAD signal that is applied to a storage register 208. The storage register 208 is then loaded with all of the data stored in the shift register 202. In the embodiment shown in FIG. 3 in which four 10-bit packet words are shifted into the shift

register 202, the storage register 208 receives and stores a 40-bit command word. However, in the more general case, the shift register 202 has N stages, each of which has a width of M bits, and the storage register 208 loads an M*N bit command word. After the storage register 208 has been loaded, it continuously outputs the M*N bit command word Y<0:39>.

As explained above, at high operating speeds, it is important that the SHIFT signal be applied to the shift register 202 at the proper time so that it latches signals on the command bus 204 when valid packet words are present on the command bus 204. If, for example, the shift register 202 is clocked by SHIFT pulses during a transition from one packet word to the next, spurious data will be shifted into the shift register 202. It is particularly difficult to ensure that the SHIFT pulses are generated at the proper time because the propagation delay of both the external clock signal CKEXT and the command packet CA is difficult to either predict or control. Furthermore, even if the propagation delay of both the external clock signal CKEXT and the command packet CA could be precisely controlled, it would be difficult to precisely control or predict the propagation delay of these signals within a memory device using the command buffer and clock generator circuit 200.

The command buffer and clock generator circuit 200 illustrated in FIG. 3 is able to precisely control the timing of the SHIFT pulses using a clock control circuit 210 which generates the internal clock signal ICLK from the external clock signal CKEXT. More specifically, the clock control circuit 210 adaptively external clock signal CKEXT and generating the internal clock signal ICLK so that the SHIFT pulses are applied to the shift register 202 at the proper time. As explained in greater detail below, during initialization of a memory device using the command buffer and clock generator circuit 200, an initialization packet having a known data pattern is repetitively applied to the shift register 202 along with the external clock signal CKEXT and the FLAG signal. After the four packet words of each initialization packet have been shifted into the shift register 202 and stored in the storage register 208, the bits of each packet word are applied to the clock control circuit 210. The clock control circuit 210 then determines if the shift register was successful in capturing the initialization packet. After determining whether each initialization packet was successfully captured by the shift register 202, the clock control circuit alters the delay between receipt of the external clock signal CKEXT and generating the internal clock signal ICLK. The clock control circuit 210 then once again determines if the packet words of the initialization packet were successfully captured. After repeating this procedure several times, the clock control circuit determines what delay values between CKEXT and ICLK are successful in capturing the initialization packet. The clock control circuit then uses one of these delay values as the delay between CKEXT and ICLK during normal operation of a memory device using the command buffer and clock generator circuit 200. In this manner, the clock control circuit 210 adapts to whatever external or internal delays exist in the coupling of the command packet CA and the external clock CKEXT, thereby allowing the command buffer and clock generator circuit 200 to operate at optimum speed. A similar system may be used to ensure that the data is latched into the memory device 16a responsive to the data clock DCLK (FIG. 2).

It will be understood that necessary portions of the command buffer and clock generator circuit 200 have been omitted from FIG. 3 in the interests of brevity since they are

somewhat peripheral to the claimed invention. For example, the command buffer and clock generator circuit 200 will contain circuitry for allowing the command buffer to determine if a command packet is directed to it, circuitry for pipelining command words output from the storage register 208, circuitry for generating lower level command signals from the command word, etc.

The relevant portions of the command buffer and clock generator circuit 200 are shown in greater detail in the block diagram of FIG. 4. As shown in FIG. 4, the timing control circuit 206 includes a clock circuit 220 that receives a clock signal CLK and its quadrature CLK90 from a conventional quadrature circuit 222 responsive to the internal clock signal ICLK. The internal clock signal ICLK is generated by the clock control circuit 210 from the external clock signal EXCLK, as explained above with reference to FIG. 3. The structure and operation of the clock control circuit 210 will be explained in detail with reference to FIGS. 5 and 6. The CLK and CLK90 signals are applied to a NOR gate 232 which outputs a high whenever ICLK and ICLK90 are both low.

The output of the NOR gate 232 is applied through a first inverter 234 to generate a CLK1 signal and then through a second inverter 236 to generate a CLK1* signal (the "*" symbol after a signal name is used throughout to designate the compliment of the signal).

The CLK90 and CLK signals are also applied to a NAND gate 240 which outputs a low whenever both CLK and CLK90 are high. The output of the NAND gate 240 is coupled through an inverter 242 to generate a CLK0 signal and then through a second inverter 244 to generate a CLK0* signal. These CLK0, CLK0*, CLK1, and CLK1* signals correspond to the SHIFT pulses described with reference to FIG. 3.

The clock circuit 220 also includes a pair of shift register circuits 246, 248 that are connected in series with each other to form an 8-stage shift register. The shift register circuit 246 receives the FLAG signal, and the FLAG signal is then sequentially shifted through the four stages of the shift register circuit 246 and the four stages of the shift register circuit 248 responsive to the CLK0, CLK0*, CLK1, and CLK1* signals. The FLAG signal is shifted through two stages of the shift register circuits 246, 248 each cycle of the CLK signals. Thus, when FLAG goes high, two successive F<0:7> outputs of the shift register circuits 246, 248 sequentially go high each clock cycle.

The shift register 202 shown in FIG. 4 includes ten separate shift register circuits 250a-j, each of which receives a respective bit CA0-CA9 of the incoming 10-bit packet word coupled through respective buffers 251a-j. Each of the shift register circuits 250a-j includes four shift register stages. Thus, after four clock cycles, four packet word bits CA have been shifted into each shift register circuit 250, and all four of these bits are available as a 4-bit word B<0:3>. Thus, the ten shift register circuits 250a-j collectively store and then output a 40-bit command word C<0:39>.

The storage register 208 also receives the CLK and CLK90 signals. However, bits B<0:3> for the four packet words stored in the shift register 202 are not latched into the storage register 208 until the F<3> signal is generated. The clock circuit 220 generates the F<3> signal four transitions of the CLK signal after receipt of the FLAG signal, i.e., after four command packets have been shifted into the shift register 202. The storage register then stores and continuously outputs the 40-bit command word Y<0:39>. The command word Y<0:39> is then used to control the operation of a

memory device containing the command buffer and clock generator circuit 200. As mentioned above, the command word Y<0:39> is also used by the clock control circuit 210 to select the optimum delay between receipt of the external clock signal CKEXT and generating the internal clock signal ICLK.

One embodiment of the clock control circuit 210 in accordance with the present invention, is shown in FIG. 5. As explained above, it is very difficult to clock the shift register 202 (FIGS. 3 and 4) at the proper time at the maximum speed of the command decoder 200. The function of the clock control circuit 210 is to provide an internal clock signal ICLK to the input of the quadrature circuit 222 at the proper time so that the timing control circuit 206 can clock the shift register 202 at even the fastest operating speed of the command decoder 200. However, it will be understood that the clock control circuit 210 may be used for other purposes both in dynamic random access memories and in other circuits. For example, it may be used to generate the data clock signal DCLK to accurately clock data into the memory device 16a, as explained above.

With reference to FIG. 5, the external clock CKEXT is coupled from line 42 through a receiver buffer 250 to a conventional voltage controlled delay circuit 252 and to one input of a phase detector 254. The voltage controlled delay circuit 252 couples the output of the receiver buffer 250 to an output line 256 with a delay that is a function of a control signal applied to the delay circuit 252 on line 258. Although the control signal on line 258 is an analog voltage, it will be understood that other types of control signals, including digital words, may alternatively be used. The output of the voltage controlled delay circuit 252 is applied to a multi-tap voltage controlled delay line 260.

The multi-tap voltage controlled delay line 260 couples the clock signal applied to its input on line 256 to a plurality of output lines 264a-264n. The incoming clock signal is coupled to the output lines 264 with an increasing delay from the first line 264a to the last line 264n. In the embodiment illustrated in FIG. 3, there are 17 output lines 264, but the delay line 260 may have a greater or lesser number of output lines 264. When a delay locked loop that includes the delay line 260 is locked as explained below, the signals at the first output line 264a and the last or 17th output line 264n are the inverse of each other, i.e., phased 180 degrees from each other. The signals on the 17 lines are therefore delayed by 11.25 degrees more than the signal coupled to the previous line 264. Thus, the first line 264a has a relative phase of zero degrees, the 16th line 264n-1 has a phase of 168.75 degrees and the last line 264n has a phase of 180 degrees. More specifically, a control voltage applied to the delay line 260 through line 270 is adjusted so that the phase of the signal on the last line 264n relative to the phase on the first line 264a is 180 degrees. This is accomplished by applying the first line 264a and the last line 264n to respective inputs of a phase detector 272.

As mentioned above, the delay line 260 and phase detector 272 implement a first delay locked loop. When the first delay locked loop is locked, the signal on line 264n will have a phase relative to the phase of the signal on line 264a of 180 degrees. Therefore, as mentioned above, the signal on each of the output lines 264a-264n will sequentially increase from zero degrees to 180 degrees. Although the signals on lines 264a-n are equally phased apart from each other, it will be understood that equal phasing is not required.

The clock control circuit 210 also includes a second delay locked loop formed by the phase detector 254, the voltage

controlled delay circuit 252 and the voltage controlled delay line 260. More particularly, the last output line 264n of the delay line 260 is applied through a simulated multiplexer circuit 290 and a clock driver 292 to one input of the phase detector 254. It will be recalled that the other input of the phase detector 254 receives the output of the receiver buffer 250. Like the phase detector 272, when the second delay locked loop is locked, the signals applied to the phase detector 254 are the inverse of each other. Thus, when the second loop is locked, the phase of the signal at the output of the clock driver 292 is 540 degrees (effectively 180 degrees) relative to the phase of the signal at the output of the receiver buffer 250.

The remaining output lines 264a-264n-1 of the delay line 260 are coupled to a multiplexer 310 having an output line coupled to clock driver 312. The multiplexer 310 couples the input of the clock driver 312 to any one of the output lines 264a-264n-1 as determined by respective four-bit phase command word CMDPH<0:3>. The four-bit phase command CMDPH<0:3> is generated by a phase control circuit 314 based on the command word Y<0:39> during an initialization procedure. The structure and operation of the phase control circuit 314 is described in detail in the remaining figures. The clock driver 312 is used to generate the internal clock signal ICLK which is used to derive the clock signals that are applied to the clock inputs of the shift register 202 (FIGS. 3 and 4).

The phase detectors 254, 272 are each implemented using to a phase detector circuit 330, a charge pump 332 and a capacitor 334. However, other varieties of phase detectors may alternatively be used.

The phase detector circuit 330 applies either an increase signal on line 336 or a decrease signal on line 338 to respective inputs of the charge pump 332. The phase detector circuit 330 generates the increase signal on line 336 whenever the phase of a first signal on one of its inputs relative to a second signal on the other of its inputs is less than 180 degrees. As explained below, the increase signal on line 336 causes the charge pump 332 to adjust the control voltage to increase the delay of the first signal so that the phase of the first signal relative to the phase of the second signal approaches 180 degrees. The phase detector circuit 330 generates the decrease signal on line 338, in the opposite condition, i.e., when the phase of the second signal relative to the first signal is greater than 180 degrees. The decrease signal on line 338 causes the charge pump 332 to adjust the control voltage to reduce the delay of second signal toward 180 degrees.

Although the phase detector circuit 330 may be implemented in a variety of ways, it may simply use two set-reset flip-flops (not shown) for generating the increase and decrease signals, respectively. The increase flip-flop is set by the rising edge of the first signal on one of the inputs and reset by the falling edge of the second signal on the other input. Thus, the duration that the flip-flop is set, and hence the duration of the increase signal on line 336, corresponds to the period of time that the second signal must be further delayed to have a phase of 180 degrees relative to the phase of the first signal. Similarly, the flip-flop producing the decrease signal on line 338 is set by the falling edge of the second signal and reset by the rising edge of the first signal so that the duration of the decrease signal on line 338 corresponds to the time that the second signal is delayed beyond the time that it would have a phase of 180 degrees relative to the phase of the first signal.

There are also a variety of approaches for implementing the charge pump 332. However, the charge pump 332 can be

implemented by simply applying a constant current to the capacitor 334 for the duration of each increase signal on line 336 and removing a constant current from the capacitor 334 for the duration of each decrease signal on line 338. Appropriate circuitry could also be included in either the phase detector circuit 330 or the charge pump 332 to provide hysteresis in a band when the first and second signals have relative phases of approximately 180 degrees from each other as will be apparent to one skilled in the art.

The operation of the clock control circuit 210 of FIG. 5 in the command decoder of FIG. 4 can best be explained with reference to the timing diagram of FIG. 6. As illustrated in FIG. 6, the external clock signal CKEXT on line 42 is delayed by approximately 70 degrees in passing through the receiver buffer 250 to node A (FIG. 5). Assuming that both of the delay-lock loops are locked, the signal at the output of the receiver buffer 250 is delayed by 120 degrees in passing through the voltage controlled delay circuit 252 to node B. The signal on node B is then coupled to node C with a delay of another 120 degrees and to node D with a delay of 300 degrees so that the signals at nodes C and D are phased 180 degrees apart from each other. Since the signals at nodes C and D are compared to each other by the phase detector 272, the phase detector 272 adjusts the control voltage on line 270 to ensure that the signals at nodes C and D are phased 180 degrees from each other. The other outputs from the delay line 260 have phases relative to the phase of the signal at node C that increase 11.25 degrees for each output in sequence from the first line 264a to the last line 264n.

As mentioned above, one of the first 16 output lines 264a-264n-1 of the delay lines 260 is coupled through the multiplexer 310 and the clock driver 312 to provide the internal clock signal ICLK at node E. In passing through the multiplexer 310 and the clock driver 312a, the selected output from the delay line is delayed by another 120 degrees. Thus, the signal Eo coupled from the first output line of the delay line 260 is delayed by 120 degrees, the signal E4 from the fifth output is delayed by 165 degrees, the signal E8 from the ninth output is delayed by 210 degrees, the signal E12 from the 13th output is delayed by 255 degrees, and the signal E15 from the 16th output is delayed by 288.75 degrees. Although the output signals are coupled from the delay line 260 through the multiplexer 310 and clock driver 312a with a delay, that delay is matched by the coupling of the signal from line 264n through the simulated multiplexer 290 and clock driver 292 since the same circuit is used for the simulated multiplexer 290 as the multiplexer 310 and the clock driver 292 is identical to the clock driver 312a. For this reason, and because the phase of the signal on line 264n is 180 degrees relative to the phase of the signal on line 264a, the signal at the output of the clock driver 292 at node G has a phase relative to the phase of the signal Eo at the output of the clock 312a of 180 degrees. Since the signals applied to the inputs of the phase detector 254 are the inverse of each other when the delay-locked loop is locked, the signal Eo has substantially the same phase as the signal at the output of the receiver buffer 250. Furthermore, the delay of the voltage controlled delay circuit 252 will be adjusted so that the signal Eo always has the same phase as the command clock coupled to the output of the receiver buffer 250 at A. Assuming the each packet word in the command packet is valid on the rising edge of the external clock CKEXT signal, the packet word coupled to the shift register 202 (FIG. 4) is valid on the rising edge of ICLK since ICLK is properly phased to the signal at node A and the delay through the receiver buffer 250 is substantially the same as the delays

through the buffers 251a-j. In operation, the multiplexer 310 selects one of the outputs from the delay line 260 as determined by the phase command word CMDPH<0:3> signal so that the optimum clock signal between Eo and E15 (FIG. 6) will be used as the internal clock ICLK.

In summary, the "inner" delay locked loop formed by the phase detector 272 and the voltage controlled delay circuit 260 generates a sequence of signals that have increasing phases from zero to 180 degrees. The "outer" delay locked loop formed by the phase detector 254, the voltage controlled delay circuit 252 and the delay line 260 align one of the clock signals in the sequence to the command clock. As a result, all of the clock signals at the output of the delay line 260 have respective predetermined phases relative to the phase of the command clock at node A.

Although the embodiment of the clock generator 210 illustrated in FIG. 5 uses delay-locked loops, it will be understood that other locked loop circuits, as well as circuits not using a locked loop, may be used in the clock control circuit 210.

Basically, the phase control circuit 314 determines the optimum phase command CMDPH<0:3> after two operating modes have been completed, namely a load mode and an analysis mode. In the load mode, the phase control circuit 314 sequentially increments the phase command CMDPH<0:3> to sequentially couple each tap of the delay line 310 (FIG. 5) to the ICLK driver 312 while the command decoder 200 repetitively receives initialization packets. Thus, the command decoder 200 attempts to accurately capture each initialization packet in the shift register 202 (FIG. 4) responsive to respective internal clock signals ICLK that sequentially vary in their timing relationship to the initialization packets. During the load mode, the phase control circuit 314 determines which initialization packets were successfully captured in the shift register 202. A record is then made identifying which phase commands CMDPH<0:3> (i.e. which taps of the delay line 260) caused ICLK to clock the shift register 202 at the proper time to successfully capture these initialization packets.

In the analysis mode, the phase command in the command record are evaluated. More specifically, a single phase command CMDPH<0:3> that is most likely to be able to successfully capture packet words in a command packet is selected from the phase commands that successfully captured an initialization packet. This selected phase command CMDPH<0:3> is the command that is used to generate the ICLK signal during normal operation. A block diagram of the phase control circuit 314 for generating the phase command CMDPH<0:3> is illustrated in FIGS. 7A and 7B.

With reference to FIG. 7A, an evaluation circuit 350 receives an initialization word Y<0:39>, an F<4> signal, and an initialization command CMDINIT. The F<4> signal is generated by the shift register (FIG. 4) in the clock circuit 220 one-half clock period after four initialization packet words, i.e., the entire initialization packet, have been latched into the shift register 202 and transferred to the storage register 208. The initialization word Y<0:39> is generated at the output of the storage register 208 and corresponds to the 4 packet words in each initialization packet. The initialization command CMDINIT is generated by other circuitry (not shown) in the command decoder 200 during the initialization procedure.

In operation, when the initialization command CMDINIT is active high, the evaluation circuit 350 analyzes the initialization word Y<0:39> to determine if the initialization packet has been accurately captured by the shift register 202

(FIG. 4). If the captured initialization word $Y<0:39>$ matches the initialization packet, the evaluation circuit **350** outputs an active high initialization result signal $INITRES$. The evaluation circuit also outputs a latch result signal $LATRES$ responsive to each $F<4>$ pulse as long as $CMDINIT$ is high, regardless of the state of the initialization result signal $INITRES$. As mentioned above, in the load mode of the initialization procedure, the evaluation circuit **350** evaluates 16 initialization packets that are applied to the command decoder **200** at 16 respective time relationships to the internal clock signal $ICLK$. Thus, in the load mode, the evaluation circuit outputs 16 $LATRES$ pulses and between 0 and 16 $INITRES$ signals depending on the number of initialization packets successfully captured by the shift register **202**.

Where multiple memory devices using the phase control circuit **314** are in a computer system, e.g., the computer system of FIG. 1, the evaluation circuit **350** may include means (not shown) for preventing more than one phase control circuit **314** from responding to the same initialization packets. For example, one memory device could be selected to be the first memory device to be initialized. After being initialized, the first memory device and all subsequent memory devices would enable initialization of the next memory device. Alternatively, the clock control circuits **210** of all of the memory devices in the computer system could be initialized at the same time responsive to the same 16 initialization packets.

With further reference to FIG. 7A, the initialization result $INITRES$ from each of 16 evaluations is applied to a selector circuit **354** along with two compressed result words, $COMPRESA<0:15>$ and $COMPRESB<0:15>$. The selector circuit **354** couples one of these three signals to a 16-bit register **360** responsive to signals from a selector control circuit **364**. The selector control circuit **354** is, in turn, controlled by a mode circuit **366**. The mode circuit receives an active low $RESET^*$ signal to place the phase control circuit **314** in the load mode, and an active high $LDINITRES<15>$ (load initial response) signal to transition the phase control circuit **314** to the analysis mode.

In the load mode, the mode circuit **366** controls the selector control circuit **364** so that it causes the selector circuit **354** to couple the $INITRES$ signal from the evaluation circuit **350** to the 16-bit register **360**. Also, during the load mode, the bit location at which the $INITRES$ signal is stored is controlled by a respective $LDINITRES<0:15>$ signal. Thus, for example, when the $INITRES$ signal (which indicates whether the initialization packet was successfully captured) obtained for a first phase of $ICLK$ corresponding to the first tap of the delay line **260** is applied to the register **360**, a $LDINITRES<0>$ signal causes the $INITRES$ signal to be stored in the first bit location of the register **360**. Similarly, the $INITRES$ signal obtained for a second phase of $ICLK$ corresponding to the second tap of the delay line **260** is stored in the second bit location of the register **360** responsive to a $LDINITRES<1>$ signal, etc. Finally, the $INITRES$ signal obtained for the 16th phase of $ICLK$ corresponding to the last tap of the delay line **260** is stored in the last bit location of the register **360** responsive to a $LDINITRES<15>$ signal. At this time, the register **360** stores 16 bits of information indicative of which of the 16 phases of the $ICLK$ signal corresponding to the 16 taps of the delay line **260** were successful in capturing the 16 initialization packets coupled to the command decoder **200** in the load mode. The stored information is output from the register **360** as $RES<0:15>$. As mentioned above, the $LDINITRES<15>$ signal then switches the mode circuit **366** to the analysis

mode since all of the information indicative of the capture of the initialization packets has then been loaded into the register **360**.

By way of example, the register **360** may output “0000110011111000” as $RES<0:15>$ after the completion of the load mode. The logic “1” values of $RES<3-7, 10, \text{ and } 11>$ thus indicates that the $ICLK$ signal coupled from the 4th–8th, 11th, and 12th taps of the delay line **260** were successful in capturing initialization packets.

When the $LDINITRES<15>$ signal switches the mode circuit **366** to the analysis mode, the mode circuit **366** controls the selector control circuit **364** so that it causes the selector circuit **354** to alternately apply $COMPRESA<0:15>$ and $COMPRESB<0:15>$ to the 16-bit register **360**. The 16 outputs of the register **360** are coupled to 16 NAND gates $374a-p$ which are, in turn, coupled to respective inverters $378a-p$ so that the NAND gates **374** and inverters **378** together perform AND functions. The inputs of each NAND gate **374** receive a respective bit of the register **360** and an adjacent bit of the register **360**, except for the first NAND gate $374a$, which receives the output from bit **16** of the register **360**. The outputs of the inverters are designated as $COMP<0:15>$, where $COMP<N>=RES(N)*RES(N-1)$ (except for $COMP<0>$ which is equal to $RES<15>*RES<0>$). The $COMP<N>$ signals are fed back to a respective input of the register **360**. However, the outputs of the inverters **378** are fed back differently for the $COMPRESA<0:15>$ signals and the $COMPRESB<0:15>$ signals. For $COMPRESA<0:15>$, each $COMPRESA<N>$ is equal to $COMP<N>*COMP<N-1>$. For $COMPRESB<0:15>$, each $COMPRESB<N>$ is equal to $COMP<N>*COMP<N+1>$. Further, in the analysis mode, the register **360** is controlled by the $LDCOMPRES$ signal so that the 16 bits fed back to the register **360** are loaded into the register **360** in parallel.

The operation of the selector circuit **354**, register **360**, NAND gates **374** and inverters **378** in the analysis mode is best understood using the above example of “0000110011111000” for the initial $RES<0:15>$. After these values for $RES<0:15>$ are coupled through the NAND gates **374** and inverters **378**, $COMP<0:15>$ is “0000010001111000”. It can be seen by comparing $RES<0:15>$ to $COMP<0:15>$ that $COMP<0:15>$ is the same as $RES<0:15>$ except that every “1” that is to the right of a “0” has been converted to a “0”. Thus, when the $COMP<0:15>$ signals are fed back to the register **360** as $COMPRESA<0:15>$, the each “1” that is positioned to the right of a “0” is changed to a “0”. As a result, the new values of $RES<0:15>$ are the previous values for $COMPRESA<0:15>$, i.e., “0000010001111000”. After these values for $RES<0:15>$ are coupled through the NAND gates **374** and inverters **378**, $COMP<0:15>$ becomes “0000000000111000”. However, since $COMPRESB<N>=COMP<N>*COMP<N+1>$, $COMP<0:15>$ is coupled back to the register **360** as “0000000001110000”. Thus, when the $COMP<0:15>$ signals are fed back to the register **360** as $COMPRESB<0:15>$, each “1” that is positioned to the left of a “0” is changed to a “0”. After $RES<0:15>$ is coupled back to the register once more as $COMPRESA<0:15>$, the new $RES<0:15>$ is “000000000110000”, i.e., the “1” to the right of a “0” is changed to a “0”. Finally, when this last $RES<0:15>$ is coupled back to the register once more as $COMPRESB<0:15>$, the new $RES<0:15>$ is “0000000000100000”, i.e., the “1” to the left of a “0” is changed to a “0”. When this final $RES<0:15>$ is coupled through the NAND gates **374** and the inverters **378**, the new $COMP<0:15>$ is “0000000000000000”.

With reference to FIG. 7B, a $COMP<0:15>$ of all “0” s is detected by a zero detector circuit **380**, which then generates

a phase selected signal PHSELECTED, a phase selected done signal PHSELDONE, and a DONE signal, each of which signifies that the optimum phase of the internal clock signal ICLK has been determined. At this time, a result select encoder 386 determines from the final RES<0:15> of "000000000100000" that the 6th bit of the register, i.e., RES<5> is the location in the register 360 that contains a "1". The result select encoder 386 then outputs a corresponding binary value P<0:3> of "0101". The result select encoder 386 also arbitrates between a result in which two or more "1"s are in the final RES<0:15>. For example, an initial RES<0:15> of "0111001110011100" would produce a final RES<0:15> of "0010000100001000" thereby providing an indication that three phases of ICLK are equally likely of capturing a command packet. The result select encoder 386 selects the lowest order "1" as the final result so that a final RES<0:15> of "0010000100001000" would be interpreted as "0000000000001000".

As mentioned above, when the final RES<0:15> is obtained, the zero detector circuit 380 outputs PHSELECTED, PHSELDONE, and DONE signals. The PHSELECTED signal causes a multiplexer to couple the P<0:3> word from the result select encoder 386 to a PHASEOUT<0:3> word that is stored in a latch 394 responsive to the PHSELDONE signal. The latch 394 then outputs the P<0:3> word corresponding to the final RES<0:15> as the phase command CMDPH<0:3>. As explained above, the phase command CMDPH<0:3> is used by the multiplexer 310 (FIG. 5) to select one of the taps of the delay line 260 to generate the internal clock signal ICLK. In the example given above where P<0:3> is "0101", the multiplexer 310 would select the sixth tap of the delay line 260 to generate ICLK.

The multiplexer 390 and latch 394 are also used in the load mode to cause the multiplexer 310 to sequentially select each of the taps of the delay line 260. Since PHSELECTED

load initial results signals LDINITRES<0:15>. As explained above, the LDINITRES<0:15> signals are used by the register 360 to determine the bit of the register 360 in which an INITRES signal from the evaluation circuit 350 is stored. Thus, the counter output E<0:3> is initially "0000" to cause the LDINITRES<0> signal to be "1" and the LDINITRES<1:15> signals to be "0", thereby causing the evaluation result INITRES from receipt of the first initialization packet to be stored as bit zero in the register 360. As the same time, the counter output E<0:3> of "0000" is coupled through the multiplexer 390 and the latch 394 so that the phase command CMDPH<0:3> is "0000". The "0000" value of CMDPH<0:3> causes the multiplexer 310 to select the first tap of the delay line 260 to generate ICLK. After the counter 400 has been incremented to 15, i.e., "1111", CMDPH<0:3> also becomes "1111" thereby causing the multiplexer 310 to select the last tap of the delay line 260 to generate ICLK. At the same time the "1111" value of E<0:3> causes the decoder 412 to output an active high LDINITRES<15> to cause the INITRES from the evaluation circuit to be stored in bit 15 of the register 360. As mentioned above, the active high LDINITRES<15> also causes the mode circuit 366 (FIG. 7A) to transition to the analyze mode, since the initial results obtained in the load mode have now been loaded into the register. The phase control circuit 314 shown in FIGS. 7A and 7B thus adapts itself to use the ICLK phase that is most likely to be successful in capturing a command packet in normal operation.

The circuitry used in the block diagram of FIGS. 7A and 7B is shown in greater detail in FIGS. 8–16. With reference to FIG. 8, the evaluation circuit 350 is specifically adapted to detect a predetermined initialization packet. In the embodiment of FIG. 8, the initialization packet that the evaluation circuit 350 is adapted to detect is shown in Table 1, below.

TABLE 1

	Flag	CA0	CA1	CA2	CA3	CA4	CA5	CA6	CA7	CA8	CA9
PW1	1	1	0	1	0	1	0	1	0	1	0
PW2	1	0	1	0	1	0	1	0	1	0	1
PW3	0	1	0	1	0	1	0	1	0	1	0
PW4	0	0	1	0	1	0	1	0	1	0	1

is inactive low prior to the end of the analyze mode, the multiplexer 390 couples the E<0:3> word from a 4-bit counter 400 to the input of the Latch 394. The inactive low PHSELDONE signal generated prior to the end of the analyzer mode causes the latch 394 to couple PHASEOUT<0:3> (corresponding to E<0:3>) through the latch 394 as CMDPH<0:3>. The CMDPH<0:3> word determines which tap of the delay line 260 is selected to generate ICLK.

The 4-bit counter 404 is enabled by an active low RESET* signal which, as explained above, occurs in the load mode. The counter 400 is incremented by each LATRES pulse which, as explained above, is generated by the evaluation circuit 350 (FIG. 7A) each time an initialization packet is received. Thus, as each initialization packet is received in the load mode, the counter 400 is incremented by one. The count of the counter 400 is coupled through the multiplexer 390 to the latch 394. The CMDPH<0:3> signals at the output of the latch 394 then sequentially selects each tap of the delay line 260 as the counter 400 is incremented. The count of the counter 400, i.e., E<0:3> is also applied to a predecoder 410 and decoder 412 to generate corresponding

The initialization packet thus consists of four packet words, PW1–PW4, arranged in a checkerboard pattern, with the first two packet words, PW1 and PW2, having a flag bit. The initialization packet shown in Table 1, if successfully captured by the shift register 202 (FIG. 4), produces an initialization word Y<0:39> in which the initialization bits alternate between 0 and "1" from Y<0> to Y<39>. The initialization bits that should be a logic "1" are applied to the gate of a respective first NMOS transistor 420 through a respective inverter 422. Although only one NMOS transistor 420 and one inverter 422 is shown in FIG. 8, there are actually 20, i.e., one for each initialization bit that should be "1". The NMOS transistors 420 for all of the initialization bits are connected between CNODE and EVAL. Similarly, The initialization bits that should be a logic "0" are applied directly to the gate of a respective second NMOS transistor 428. Once again, although only one NMOS transistor 428 is shown in FIG. 8, there are actually 20, i.e., one for each initialization bit that should be "0". The NMOS transistors 428 for all of the initialization bits are also connected between CNODE and EVAL.

After each initialization word $Y<0:39>$ has been captured, the EVAL node is pulled to ground by turning ON an NMOS transistor **430**. The transistor **430** is turned ON by a pulse from a pulse generator **432** which is, in turn, triggered by a falling edge from a NAND gate **434**. As mentioned above with reference to FIG. 7A, the CMDINT signal is active high during initialization, thereby enabling the NAND gate **434**. However, the NAND gate **434** initially outputs a high because the $F<3>$ signal from the clock circuit **220** (FIG. 4) and $F<4>$ coupled through a pair of inverters **436**, **438** are initially low. Further, since there is generally a FLAG signal sent with only the first packet word of a command packet, $F<3>$ and $F<4>$ are generally never high at the same time. However, as shown in Table 1, a FLAG signal is sent with the first two initialization words of each initialization packet. Thus, for initialization packets, $F<3>$ and $F<4>$, even after being delayed through the inverters **436**, **438**, are both high for a short time after the initialization word has been stored in the storage register **208** (FIG. 4). At this time, the output of the NAND gate **434** goes low, thereby triggering the pulse generator **432** to turn ON the transistor **430** and pull the EVAL node low.

The pulse from the pulse generator **432** during each initialization packet also triggers a pulse generator **440** which generates the latch results pulse LATRES through a pair of inverters **442**, **444**. As explained above with reference to FIG. 7B, each LATRES pulse clocks the counter **400** in the load mode to specify the register bit in which an initial results signal INITRES is to be stored and to specify to the multiplexer **310** (FIG. 5) which tap of the delay line **260** should be selected. Each LATRES pulse, in turn, triggers another pulse generator **450** which generates a NEXTPH pulse.

The NEXTPH pulse is coupled through an inverter **460** to the gate of a PMOS transistor **462** to turn ON the transistor **462** and pull CNODE high. The high on CNODE is then latched by a latch, formed by a pair of inverters **470**, **472**, which maintains CNODE high. CNODE can also be pulled high by a PMOS transistor **466** responsive to a reset signal R^* .

After CNODE has been latched high, it will be pulled low if either of the NMOS transistors **420**, **238** turns ON. However, if the initialization packet is successfully captured by the shift register **202** (FIG. 4), neither of the NMOS transistors **420**, **428** will turn on so that CNODE will be maintained high. As a result, the latch formed by the inverters **470**, **472**, generates an active high initial results signal INITRES. Thus, INITRES will be high if the initialization packet was successfully captured by the shift register **202** (FIG. 4), and low if there is an error in any of the initialization bits as captured by the shift register **202**.

As explained above with reference to FIG. 7A, the INITRES signal is stored in the 16 bit register **360**. The register **360**, as well as the selector circuit **354**, is shown in greater detail in FIG. 9. The selector circuit **354** and register **360** includes 16 separate selectors $354a-p$ and 16 separate register circuits $360a-p$, only one of which $354a$ and $360a$ is shown in detail in FIG. 9.

A separate register circuit **360** is provided to store each of the 16 INITRES signals, and a separate selector **354** is provided to couple each INITRES signal to its respective register circuit **360**. With reference to FIG. 9, in the load mode, an active high ENRES signal and an active low $ENRES^*$ signal enable a pass gate **480** in the selector **354** to couple the INITRES signal to the input of the register **360**. During this time, the ENCRESA and ENCRESB signals are

inactive low and the ENCRESA* and ENCRESB* signals are inactive high to disable respective pass gates **484**, **488**. As also explained above with reference to FIG. 7A, a plurality of load initial results signals $LDINITRES^*<0:15>$ are provided for the respective register bits, and the $LDINITRES^*$ signal for each register bit is driven low after an INITRES signal corresponding to that bit is obtained. The active low $LDINITRES^*$ signal causes a NAND gate **490** in the corresponding register circuit **360** to output a high which disables a pass gate **494** and enables a pass gate **496**, directly and through an inverter **498**. The INITRES signal coupled through the pass gate **480** is then stored in a latch formed by a pair of inverters **500**, **502**, and the output of the latch is coupled through the pass gate **496** to a latch formed by a pair of inverters **506**, **508**. The $RES<0:15>$ outputs from the register **360** are thus each "1" if the INITRES signal is indicative of the initialization packet being successfully captured is "1".

The operation of the register **360** and the selector circuit **354** in the analysis mode will now be explained. In the analysis mode, ENRES is inactive low and $ENRES^*$ is inactive high to disable the pass gate **480** and isolate the INITRES signal from the register **360**. However, ENCRESA and ENCRESB are alternately active high and $ENCRESA^*$ and $ENCRESB^*$ are alternately active low so that the pass gates **484**, **488** are alternately enabled. As a result, as explained above with reference to FIG. 7A, $COMPRESA<0:15>$ and $COMPRESB<0:15>$ are alternately coupled to their respective inputs of the register **360**. As also explained above with reference to FIG. 7A, in the analyze mode, the $LDCOMPRES^*$ signal is driven low after each compression iteration. The active low $LDCOMPRES^*$ signal triggers the latch to store either $COMPRESA$ or $COMPRESB$ in the register **360** in the same manner that $LDINITRES^*$ causes the INITRES signal to be stored in the register **360**, as explained above.

The mode circuit **366** and the selector control circuit **354** are illustrated in FIG. 10. A flip-flop **520** formed by a pair of NAND gates **522**, **524** is initially reset by an active low $RESET^*$ signal generated by means (not shown) located elsewhere in the command decoder **200**. For example, the $RESET^*$ signal may be generated at power-up or periodically, as is well known in the art. When the flip-flop **520** is reset, it outputs a high which is coupled through inverters **528**, **530**, **532** to generate an active high ENRES signal and an active low $ENRES^*$ signal. As explained above, these signals place the phase control circuit **314** in the load mode by coupling the INITRES signal to the register **360**.

The high at the output of the reset flip-flop **520** is coupled through the inverter **528** to cause a pair of NAND gates **536**, **538** to output respective high signals. The high at the output of the NAND gate **536** is coupled through a pair of inverters **540**, **542** to generate an inactive low ENRESA signal and an inactive high $ENRESA^*$ signal. Similarly, the high at the output of the NAND gate **538** is coupled through a pair of inverters **546**, **548** to generate an inactive low ENRESB signal and an inactive high $ENRESB^*$ signal. As explained above with reference to FIGS. 7A and 8, these signals isolate the $COMPRESA$ and $COMPRESB$ signals from the register **360** in the load mode.

As explained above with reference to FIG. 7, the active low $LDINITRES^*<15>$ signal is generated to load the final initial results signal INITRES into the last bit of the register **360**. The $LDINITRES^*<15>$ signal also triggers a pulse generator **550** through an inverter **552** to generate a pulse a short time after $LDINITRES^*<15>$ causes the final INI-

TRES to be loaded in the register 360. This pulse is coupled through an inverter 554 to set the flip-flop 520, thereby placing the phase control circuit 314 in the analyze mode.

In the analyze mode, the high at the output of the inverter 528 drives ENRES inactive low and ENRES* inactive high. The high at the output of the inverter 528 also enables the NAND gates 536, 538. The NAND gate 538 receives the output of a register 560, while the NAND gate 536 receives its complement from an inverter 562. The output of the inverter 562 is also applied to the input of the register 560. As a result, when the register 560 is successively clocked, the output of the register toggles between "0" and "1". When the output of the register 560 is "1", the NAND gate 538 causes ENCRESB to be active high and ENCRESB* to be active low. When the output of the register 560 is "0", the NAND gate 536 causes ENCRESA to be active high and ENCRESA* to be active low. Thus, as the register 560 is clocked, the COMP<0:15> signals (FIG. 7A) are fed back to the inputs of the register 360 alternately as COMPRESA<0:15> and COMPRESB<0:15>, as explained above with reference to FIG. 7A.

The register 560 is clocked by the LDCOMPRES* signal, directly and through an inverter 564. The LDCOMPRES* signal is generated at the output of an inverter 566 responsive to a pulse from a pulse generator 568. The pulse generator 568 is, in turn, triggered by the output of a NAND gate 570. The NAND gate 570 is enabled by an inactive high DONE* signal which is present until the analysis mode had determined which tap of the delay line 260 (FIG. 5) is to be used to generate ICLK. The other input of the NAND gate 570 is coupled to the output of a NOR gate 572 through an inverter 574. The NOR gate 572 triggers the pulse generator 568 responsive to a pulse from either of two delay circuits 574, 576 which receive the ENCRESA and ENCRESB signals, respectively. The delay provided by the delay circuits 574, 576 allows sufficient time for ENCRESA, ENCRESB and their complements to enable their respective pass gates 484, 488 (FIG. 9) to couple COMPRESA and COMPRESB to the latch formed by the inverters 500, 502 before the LDCOMPRES* is generated to store COMPRESA and COMPRESB in the latch. Thus, when ENCRESA is generated at the output of the inverter 540, it toggles the register 560 so that ENCRESB is generated after ENCRESA has loaded COMPRESA<0:15> into the register 360. ENCRESB then causes COMPRESB<0:15> to be loaded into the register 360 and toggles the register 560 to generate ENCRESA, etc. This process continues until all of the bits of COMP<0:15> are logic "0". At this time, the output of the register 360 RES<0:15> specifies the tap of the delay line 260 that will be used in normal operation, and the zero detector circuit 380 (FIG. 7B) outputs an active low DONE* signal. The active low DONE* signal applied to the input of a NOR gate 578 causes the PHSELECTED signal to go high. As explained above with reference to FIG. 7B, the PHSELECTED signal causes the multiplexer 390 to couple the final RES<0:15> to the multiplexer 310 to select the delay line tap that will be used during normal operation of the memory device containing the command buffer and clock generator circuit 200.

The zero detector circuit 380 is implemented by four 4-input NOR gates 590-596 which drive a 4-input NAND gate 598, thereby creating a 16-input OR gate. When the RES<0:15> signals contain only single "1"s, i.e., there are no "1"s adjacent each other, the resulting COMP<0:15> signals will all be "0". If each group of 4 COMP<0:15> signals

applied to a respective NOR gate 590-596 are all "0", then the outputs of the NOR gates 590 will all be high, thereby causing the NAND gate 598 to output an active low DONE* signal. As explained above, the active low DONE* signal indicates that the analysis mode has determined which tap of the delay line 260 is to be used to generate ICLK during normal operation.

The 4-bit counter 400 and predecoder 410 (FIG. 7B) are illustrated in greater detail in FIG. 12. As described above, the counter 400 is incremented by each LATRES pulse which is generated by the evaluation circuit 350 (FIG. 8) each time an initialization packet is received. Thus, as each initialization packet is received in the load mode, the counter 400 is incremented by one. As described above with reference to FIG. 7, the count of the counter 400 is coupled through the multiplexer 390 and latch 394 to sequentially select each tap of the delay line 260 as the counter 400 is incremented. The count of the counter 400, is also applied to the predecoder 410 and decoder 412 to generate a corresponding load initial results signals LDINITRES<0:15> which specifies the bit of the register 360 in which each INITRES signal from the evaluation circuit 350 is stored.

The counter 400 is implemented in a conventional manner by four registers 500-506 each of which has a RESET* input, an output fed back to its input by a respective inverter 508, and a pair of clock inputs CLK and CLK*.

The first register 500 is clocked by a pulse generator 510 through a pair of inverters 512, 514 responsive to each latch result signal LATRES. Thus, the first register 500 toggles each LATRES pulse. It will be recalled that the LATRES signal is generated by the evaluation circuit 350 (FIG. 8) each time an initialization packet is received. The remaining registers 502-506 are clocked by the output of the prior register 500-506, respectively, so that their respective outputs toggle every other time the output of a prior register transitions from high to low. Thus, the value of the E<0:3> output signals from the counter 400 increment once for each LATRES pulse, i.e., each time an initialization packet has been received.

The output of the counter 400 is applied to the predecoder 410 which is also illustrated in FIG. 12. The predecoder 410 uses a NOR gate 522 to drive ZERO high only if E<0> or E<1> are both low. Thus, ZERO is high only if the count of the counter is 0, 4, 8, or 12. The ONE output is generated by a NOR gate 522 that receives the E<1> and the inverted E<0> signal coupled through an inverter 524. The output of the NOR gate 522 is high only if E<1> is low and E<0> is high. Thus, ONE is high only if the count of the counter is 1, 5, 9, or 13. The TWO output of a NOR gate 528 will be high only if E<0> is low and E<1> applied to the NOR gate 528 through an inverter 530 is high. Thus, TWO is high only if the count of the counter is 2, 6, 10, or 14. Finally, the THREE signal at the output of an inverter 532 will be high only if the E<0> and E<1> signals applied to the inputs of a NAND gate 534 are both high. Thus, THREE is high only if the count of the counter is 3, 7, 11, or 15.

The FOUR, FIVE, SIX and SEVEN signals are generated by decoding E<2> and E<3> using the same circuitry that is used to decode E<0> and E<1> to obtain the ZERO, ONE, TWO and THREE signals. Thus, in the interests of brevity, an explanation of decoding of E<2> and E<3> will be omitted. However, the outputs of the predecoder 410 are as specified in Table 2, below.

TABLE 2

COUNT	SEVEN	SIX	FIVE	FOUR	THREE	TWO	ONE	ZERO
0	0	0	0	1	0	0	0	1
1	0	0	0	1	0	0	1	0
2	0	0	0	1	0	1	0	0
3	0	0	0	1	1	0	0	0
4	0	0	1	0	0	0	0	1
5	0	0	1	0	0	0	1	0
6	0	0	1	0	0	1	0	0
7	0	0	1	0	1	0	0	0
8	0	1	0	0	0	0	0	1
9	0	1	0	0	0	0	1	0
10	0	1	0	0	0	1	0	0
11	0	1	0	0	1	0	0	0
12	1	0	0	0	0	0	0	1
13	1	0	0	0	0	0	1	0
14	1	0	0	0	0	1	0	0
15	1	0	0	0	1	0	0	0

The output signals from the predecoder **410** are further decoded by coder **412** (FIG. 7) to generate each of the load initial result signals LDINITRES* $\langle 0:15 \rangle$. As explained above with reference to FIG. 7B, each LDINITRES* $\langle N \rangle$ signal loads the initial result INITRES from the evaluation circuit **350** into the N bit of the register **360**. As shown in FIG. 13, the decoder **412** includes **16** NAND gates, indicated collectively by reference numeral **540**. Each of the NAND gates **540** receives a unique combination of two inputs from the predecoder **410**, and all of the NAND gates **540** receive the LATRES signal. It will be recalled that the LATRES signal is generated by the evaluation circuit **350** (FIG. 8) each time an initialization packet is received. However, only one of the NAND gates **540** will output an active low LDINITRES* signal since only one NAND gate **540** will be enabled by both of its inputs from the predecoder **410** being high. The active low LDINITRES* signal then loads the INITRES signal in the bit of the register corresponding to the count designated by the outputs from the predecoder **410**. The manner in which the NAND gates **540** accomplish this function will be apparent to one skilled in the art from FIG. 13 and Table 2.

As explained above with reference to FIG. 7B, the function of the result select encoder **386** is to arbitrate between a situation in which two or more "1"s are in the final RES $\langle 0:15 \rangle$. There will only be one "1" in the final RES $\langle 0:15 \rangle$ as long as there is only one set of "1"s in the initial RES $\langle 0:15 \rangle$ having the maximum length. However, if there are two or more sets in the initial RES $\langle 0:15 \rangle$ that have the same number of "1"s, then the final RES $\langle 0:15 \rangle$ will contain more than one "1". The result select encoder **386** selects the lowest "1" in the final RES $\langle 0:15 \rangle$ and forces the other "1"s to "0". The result select encoder **386** is shown in greater detail in FIG. 14.

With reference to FIG. 14, the result select encoder **386** includes an inverter **550** and a set of NAND gates **522–578** that each receive a respective RES $\langle 0:14 \rangle$ bit and one or more signals from the output of the inverter **550** or NAND gates **522–578** receiving lower order RES bits. The inverter **550** outputs a low if RES $\langle 0 \rangle$ is high. However, the NAND gates **522–578** can output a low responsive to its respective RES input being high only if it is not disabled by one or more signals from the inverter **550** or NAND gates **522–578** receiving lower order RES bits. If the inverter **550** or any of the NAND gates **522–578** outputs a low, it disables all of the NAND gates **522–578** that receive higher order RES bits. Thus, for example, if RES $\langle 0 \rangle$ is "1", the low at the output of the inverter **550** disables the NAND gates **552, 554**. The

low at the output of the inverter **550** is also applied to a NAND gate **590** which causes a low to be generated at the output of an inverter **592**. The inverter **592** will also output a low if the outputs of either NAND gate **552** or NAND gate **554** goes low responsive to a high RES $\langle 1 \rangle$ or RES $\langle 2 \rangle$, respectively. The low at the output of the inverter **592** disables the NAND gates **556, 558**, and it is also applied to a NAND gate **594** to cause an inverter **596** to output a low. The low at the output of the inverter **596**, in turn, disables NAND gates **560, 562**, and is applied to a NAND gate **602** to cause an inverter **604** to output a low. The low at the output of the inverter **604**, in turn, disables NAND gates **564, 566**, and is applied to a NAND gate **606** to cause an inverter **608** to output a low. The low at the output of the inverter **608** disables NAND gates **568, 570**, and is applied to a NAND gate **610** to cause an inverter **612** to output a low. The low at the output of the inverter **612** disables NAND gates **572, 574**, and is applied to a NAND gate **614** to cause an inverter **616** to output a low. Finally, the low at the output of the inverter **616** disables NAND gates **576, 578**. Thus, only the output of the inverter **550** will be low, regardless of how many RES bits in addition to RES $\langle 0 \rangle$ are high.

The outputs of the inverter **550** and the NAND gates **522–578** are applied to a set of NAND gates **620–634** that, in turn, drive four NOR gates **670–678**. The function of these NAND gates **620–632** and NOR gates **670–678** is to generate the a binary number P $\langle 0:3 \rangle$ corresponding to the compliment of whichever inverter **550** or NAND gate **522–578** is outputting a low. The inverter **550** or NAND gate **522–578**, in turn, is indicative of the lowest order RES bit that is "1". Thus, for example, the NAND gates **620, 622** together decode RES $\langle 0,2,4,6,8,10,12,14 \rangle$. The NAND gates **632, 634** together decode RES $\langle 8:15 \rangle$.

Either the P $\langle 0:3 \rangle$ or the E $\langle 0:3 \rangle$ signals from the counter **400** are coupled by the multiplexer **390** (FIG. 7B) to the latch **394**. The multiplexer **390** is shown in FIG. 15. The P $\langle 0:3 \rangle$ signals are applied through respective inverters **700** to respective pass gates **702** which are coupled to the inputs of respective inverters **704**. Similarly, The E $\langle 0:3 \rangle$ signals are applied through respective inverters **706** to respective pass gates **708** which are also coupled to the inverters **704**. The pass gates **702** are enabled directly and through an inverter **710** by PHSELECTED being active high. When the pass gates **702** are enabled, the P $\langle 0:3 \rangle$ signals are coupled to the inverters **704**. When PHSELECTED is inactive low, the pass gates **708** are enabled to couple the E $\langle 0:3 \rangle$ signal to the inverters **704**. The inverters **704** thus output as PHASEOUT $\langle 0:3 \rangle$ either P $\langle 0:3 \rangle$ or E $\langle 0:3 \rangle$, depending on

the state of PHSELECTED. As explained above, PHSELECTED is low during the initialization procedure so that the E<0:3> signals from the counter 400 select the tap of the delay line 260 and select the bit of the register 360 in which each IMTRES is stored. However, once the optimum delay line tap has been selected in the analysis mode, PHSELECTED goes high to select P<0:3> corresponding to the final RES<0:15> to designate the tap of the delay line 260.

The multiplexer 390 also includes a delay circuit 720 receiving the PHSELECTED signal and driving a pair of inverters 722, 724 to generate PHASEDONE a short time after PHSELECTED is generated.

The PHASEOUT<0:3> signals from the multiplexer 390 are applied to the latch 394 (FIG. 7B), which is shown in greater detail in FIG. 16. The PHASEOUT<0:3> signals are applied to respective latch circuits 730-736. The outputs of the latch circuits 730-736 are applied to respective pass gates 740-746 which are coupled to respective inverter pairs 750-756. The latch circuits 730-736 may be selectively bypassed by respective pass gates 760-766. The pass gates 740-746 and the pass gates 760-766 are connected to each other so that the pass gates 740-746 are enabled alternately with the pass gates 760-766.

As explained earlier, in the load mode the initiation command CMDINIT is high, thereby enabling the pass gates 760-766 directly and through an inverter 770. As a result, the latches 730-736 are bypassed in the load mode so that the phase command CMDPH<0:3> applied to the multiplexer 310 (FIG. 5) to select the tap of the delay line 260 always corresponds to PHASEOUT<0:3>. However, when the final RES<0:15> has been obtained, PHSDONE goes high, thereby triggering a pulse generator 774 through an inverter 776. The pulse generated by the pulse generator 774 is applied to the S inputs of the latch circuits 730-736 and its complement is applied through an inverter 778 to the S* inputs of the latch circuits 730-736. The latch circuits 730-736 then store the PHASEOUT<0:3> signals that correspond to the P<0:3> signals selected by the multiplexer 390. The P<0:3> signals, in turn, correspond to the lowest order final result RES<0:15> containing a "1". The PHASEOUT<0:3> signals stored in the latch circuits 730-736 are then coupled to the inverter pairs 750-756 by the pass gates 740-746 since CMDINIT has gone low by this time. The latch circuits 730-736 store the PHASEOUT<0:3> signals until either new PHASEOUT<0:3> signals are stored in the latch circuits 730-736 or they are reset by the RESET* signal applied through a pair of inverters 780, 782. The CMDPH<0:3> then causes the multiplexer 310 (FIG. 5) to select the tap of the delay line 260 that will be used to generate ICLK during normal operation.

Although the preferred embodiment of the invention has been described primarily as being used to adjust the phase of an internal clock signals to accurately latch an externally applied command packet, it will be understood that it may be used for similar purposes in memory devices and other types of integrated circuits. For example, as explained above, the same system may be used to adjust the phase of an internal data clock relative to the external data clock DCLK received on line 132 (FIG. 2) to accurately latch data on the data bus 130. In fact, the system may be used to adjust the timing of clock signals to accurately latch any type of input signals applied to any type of integrated circuit. In fact, the system could be used with little additional circuitry to select a respective clock phase that could best latch every input signal that is applied to an integrated circuit. In such case, the system would sequentially evaluate every input terminal of the integrated circuit in the same manner that the

command bus was evaluated to determine the optimum clock phase for capturing command packets on the command bus.

From the foregoing it will be appreciated that, although specific embodiments of the invention have been described herein for purposes of illustration, various modifications may be made without deviating from the spirit and scope of the invention. Accordingly, the invention is not limited except as by the appended claims.

We claim:

1. A method of adaptively adjusting the phase of an internal clock signal relative to an external clock signal, the internal clock signal triggering a latch to store a digital signal, the method comprising:

repetitively applying digital signals to the latch having a predetermined value;

storing the digital signals in the latch responsive to different respective phases of the internal clock signal;

evaluating the digital signals stored in the latch to determine if the stored digital signals have the predetermined value;

identifying each phase of the internal clock signal that caused the latch to store a digital signal having the predetermined value;

selecting a phase of the internal clock signal that caused the latch to store a digital signal having the predetermined value; and

adjusting the phase of the internal clock signal to the selected phase.

2. The method of claim 1 wherein the step of selecting one of the phases that caused the latch to store digital signals having the predetermined value comprises:

designating each of the phases of the internal clock signal that caused the latch to store digital signals having the predetermined value with an associated first logical value;

designating each of the phases of the internal clock signal that caused the latch to store digital signals having other than the predetermined value with an associated second logical value;

arranging all of the logical values in a series in which each of the logical values have a position corresponding to the phases of the internal clock signal that caused the latch to store the digital signals associated with the logical values;

repetitively changing in sequence each first logical value that is to the right of a second logical value to the second logical value and each first logical value that is to the left of a second logical value to the second logical value until each of the remaining first logical values is surrounded by the second logical values; and

selecting the phase of the internal clock signal to correspond to the position of a remaining first logical value.

3. The method of claim 2 wherein the first logical value comprises a logical "1" and the second logical value comprises a logical "0".

4. The method of claim 2 wherein the step of selecting the phase of the internal clock signal to correspond to the position of a remaining first logical value comprises:

examining the sequence of logical values in which each of the remaining first logical values is surrounded by the second logical values;

changing all of the first logical values in the sequence that are positioned to one side of a first logical value to the second logical value; and

selecting the phase of the internal clock signal to correspond to the position of the unchanged first logical value.

5. The method of claim 1 wherein the step of repetitively applying digital signals to the latch comprises repetitively applying an initialization packet containing a plurality of initialization packet words to the latch, and storing each of the initialization packets in the latch responsive to respective to different transitions of the internal clock signal.

6. The method of claim 1 wherein the step of determining which phases of the clock signal caused the latch to store digital signals having the predetermined value, comprises:

designating each of the digital signal stored in the latch that has the predetermined value as being a correctly captured digital signal;

pairing each correctly captured digital signal with a respective phase of the internal clock signal that caused the correctly captured digital signal to be stored in the latch; and

designating each phase of the internal clock signal that is in each pairing of a correctly captured digital signal and a phase of the internal clock signal as a phase of the internal clock signal that caused the latch to store a digital signal having the predetermined value.

7. The method of claim 1 wherein the latch comprises an input stage of a shift register that shifts each digital signal sequentially applied to the shift register into the register and from one shift register stage to the next.

8. The method of claim 1 wherein the step of selecting a phase of the internal clock signal that caused the latch to store a digital signal having the predetermined value comprises selecting from among a plurality of phases of the internal clock signal that caused the latch to store respective digital signals having the predetermined value.

9. A method of adaptively adjusting the phase of an internal clock signal relative to an external clock signal, the method comprising:

repetitively receiving a digital signal;

latching a plurality of the received digital signals responsive to respective phases of the internal clock signal;

examining each of the latched digital signals to determine if it was accurately latched;

selecting a phase of the internal clock signal that is within the range of phases of the internal clock signal that accurately latched respective digital signals.

10. The method of claim 9 wherein the step of selecting a phase of the internal clock signal that is within the range of phases of the internal clock signal that accurately latched respective digital signals comprises:

designating each of the phases of the internal clock signal that accurately latched the respective digital signals with an associated first logical value;

designating each of the phases of the internal clock signal inaccurately latched the respective digital signals with an associated second logical value;

arranging all of the logical values in a series in which each of the logical values have a position corresponding to the phases of the internal clock signal that latched the respective digital signals;

repetitively changing in sequence each first logical value that is to the right of a second logical value to the second logical value and each first logical value that is to the left of a second logical value to the second logical value until each of the remaining first logical values is surrounded by the second logical values; and

selecting the phase of the internal clock signal to correspond to the position of a remaining first logical value.

11. The method of claim 10 wherein the first logical value comprises a logical "1" and the second logical value comprises a logical "0".

12. The method of claim 10 wherein the step of selecting the phase of the internal clock signal to correspond to the position of a remaining first logical value comprises:

examining the sequence of logical values in which each of the remaining first logical values is surrounded by the second logical values;

changing all of the first logical values in the sequence that are positioned to one side of a first logical value to the second logical value; and

selecting the phase of the internal clock signal to correspond to the position of the unchanged first logical value.

13. The method of claim 9 wherein the step of repetitively receiving a digital signal comprises repetitively receiving an initialization packet containing a plurality of initialization packet words, and storing each of the initialization packets in a latch responsive to respective to different transitions of the internal clock signal.

14. The method of claim 9 wherein the step of selecting a phase of the internal clock signal that is within the range of phases of the internal clock signal that accurately latched respective digital signals comprises:

pairing each accurately latched digital signal with a respective phase of the internal clock signal that caused the digital signal to be accurately latched; and

selecting from among each phase of the internal clock signal that is in each pairing of an accurately latched digital signal and a phase of the internal clock signal.

15. The method of claim 9 wherein the step of selecting a phase of the internal clock signal that accurately latched a digital signal comprises selecting from among a plurality of phases of the internal clock signal that accurately latched respective digital signals.

16. A system for adaptively adjusting the phase of an internal clock signal that causes a latch to store a digital signal responsive to the internal clock signal, comprising:

a clock control circuit controlling the phase of the internal clock signal relative to an external clock signal responsive to a phase command signal;

a load control circuit generating a plurality of phase command signals responsive to receiving respective digital signals, each of the phase command signals corresponding to different respective phases of the internal clock signal;

an evaluation circuit coupled to the latch, the evaluation circuit receiving a plurality of digital signals sequentially stored in the latch and determining if each of the stored digital signals has a predetermined value, the evaluation circuit generating a plurality of respective results signals indicative of whether each of the digital signals has the predetermined value;

a register coupled to the evaluation circuit and the load control circuit, the register storing the results signals; and

an analysis circuit coupled to the register, the analysis circuit examining the results signals stored in the register and, based on the examination of the stored results signals, generating a final phase command signal, the final phase command signal being continuously applied to the clock control circuit.

17. The system of claim 16 wherein the analysis circuit comprises:

- a plurality of logic elements corresponding in number to the number of storage locations in the register, each of the logic elements receiving a results signal stored in a respective location in the register and a results signal stored in an adjacent location in the register, each of the logic elements producing a respective compare signal resulting from a comparison of the results signals received by the logic element;
- a feedback circuit coupling the compare signals back to the register for storage in the register, the feedback circuit alternately varying the location in which each compare signal is stored between two adjacent storage locations;
- a final results detector detecting when the compare signals have predetermined characteristics; and
- a phase command output circuit coupled to the final results detector deriving the final phase command signal from the signals stored in the register when the final results detector detects that the compare signals have the predetermined characteristics.

18. The system of claim 16 wherein the analysis circuit comprises a logic circuit coupled to the register, the logic circuit identifying a set of phase command signals corresponding to a contiguous set of clock phases that caused the latch to store digital signals having the predetermined value, the logic circuit generating as the final phase command signal a phase command signal corresponding to a clock phases within the range of clock phases that caused the latch to store digital signals having the predetermined value.

19. The system of claim 18 wherein the logic circuit generates as the final phase command signal a phase command signal corresponding to a clock phase in substantially the middle of a range of clock phases that caused the latch to store digital signals having the predetermined value.

20. The system of claim 18 wherein the logic circuit identifies the internal clock phase in substantially the middle of each of a plurality of identically sized ranges of internal clock phases that caused the latch to store digital signals having the predetermined value, and generates as the final phase command signal a phase command signal corresponding to an identified internal clock phase at one location in the range relative to the locations of all of the other identified internal clock phases in the range.

21. The system of claim 16 wherein the analysis circuit comprises:

- a plurality of logic gates corresponding in number to the number of result signals stored in respective bits of the register, each of the logic gates having a first input coupled to the respective bit of the register and a second input coupled to a bit of the register adjacent the respective bit of the register, wherein the first and last bits of the register are considered adjacent bits;
- a feedback circuit alternately coupling the output of each of the logic gates to the input of a respective bit of the register or the input of a bit of the register adjacent the respective bit of the register; and
- a final results detector coupled to the outputs of the logic gates, the final results detector detecting when all of the outputs of the logic gates have the same logic level.

22. The system of claim 16 wherein the analysis circuit comprises a set of logic gates corresponding in number to the number of result signals stored in respective bits of the register, each of the logic gates having a first input coupled to a respective bit of the register and a second input coupled

to the outputs of logic gates having respective inputs coupled to bits of the register that are positioned to one side of the bit to which the logic gate is coupled, each of the logic gates being disabled by a signal applied the second input of the gate so that only one logic gate generates an output having a first logic level responsive to signals received from respective bits of the register.

23. The system of claim 16 wherein the load control circuit comprises:

- a counter incremented each time one of the digital signals is stored in the latch, the counter generating count signals indicative of the count of the counter; and
- a decoder receiving the count signals, the decoder generating the phase command signals responsive to the count signals, the phase of the internal clock signal determined by each command signal corresponding to the count of the counter.

24. The system of claim 16 wherein the register further comprises an address circuit to store each of the results signals in the register at a location corresponding to a register address, and wherein the load control circuit further comprises an address generating circuit coupled to the register, the address generating circuit producing the register address corresponding to the count of the counter.

25. A packetized dynamic random access memory, comprising:

- a clock generator circuit generating an internal clock signal having a phase relative to an external clock signal determined by a phase command signal;
- at least one array of memory cells adapted to store data at a location determined by a row address and a column address;
- a row address circuit adapted to receive and decode the row address, and select a row of memory cells corresponding to the row address responsive to a first set of command signals;
- a column address circuit adapted to receive or apply data to one of the memory cells in the selected row corresponding to the column address responsive to a second set of command signals;
- a data path circuit adapted to couple data between an external terminal and the column address circuit responsive to a third set of command signals;
- a command buffer receiving command packets and initialization packets having a predetermined value, the command buffer including a latch storing each of the received packets responsive to a transition of the internal clock signal, the command buffer further generating a respective command words and initialization words corresponding to each received command packet and initialization packet, respectively;
- a load control circuit generating a plurality of phase command signals responsive to receipt of a plurality of respective initialization packets, each of the phase command signals corresponding to different respective phases of the internal clock signal;
- an evaluation circuit coupled to the latch, the evaluation circuit receiving a plurality of initialization words corresponding to initialization packets sequentially stored in the latch and determining if each of the initialization words has the predetermined value, the evaluation circuit generating a plurality of respective results signals indicative of whether each of the initialization words has the predetermined value;
- a register coupled to the evaluation circuit and the load control circuit, the register storing the results signals; and

an analysis circuit coupled to the register, the analysis circuit examining the results signals stored in the register and, based on the examination of the stored results signals, generating the phase command signal, the phase command signal being continuously applied to the clock generator circuit.

26. The packetized dynamic random access memory of claim 25, wherein the analysis circuit comprises:

- a plurality of logic elements corresponding in number to the number of storage locations in the register, each of the logic elements receiving a results signal stored in a respective location in the register and a results signal stored in an adjacent location in the register, each of the logic elements producing a respective compare signal resulting from a comparison of the results signals received by the logic element;
- a feedback circuit coupling the compare signals back to the register for storage in the register, the feedback circuit alternately varying the location in which each compare signal is stored between two adjacent storage locations;
- a final results detector detecting when the compare signals have predetermined characteristics; and
- a phase command output circuit coupled to the final results detector deriving the final phase command signal from the signals stored in the register when the final results detector detects that the compare signals have the predetermined characteristics.

27. The packetized dynamic random access memory of claim 25, wherein the analysis circuit comprises a logic circuit coupled to the register, the logic circuit identifying a set of phase command signals corresponding to a contiguous set of clock phases that caused the latch to store digital signals having the predetermined value, the logic circuit generating as the final phase command signal a phase command signal corresponding to a clock phases within the range of clock phases that caused the latch to store digital signals having the predetermined value.

28. The packetized dynamic random access memory of claim 27, wherein the logic circuit generates as the final phase command signal a phase command signal corresponding to a clock phase in substantially the middle of a range of clock phases that caused the latch to store digital signals having the predetermined value.

29. The packetized dynamic random access memory of claim 27, wherein the logic circuit identifies the internal clock phase in substantially the middle of each of a plurality of identically sized ranges of internal clock phases that caused the latch to store digital signals having the predetermined value, and generates as the final phase command signal a phase command signal corresponding to an identified internal clock phase at one location in the range relative to the locations of all of the other identified internal clock phases in the range.

30. The packetized dynamic random access memory of claim 25 wherein the analysis circuit comprises:

- a plurality of logic gates corresponding in number to the number of result signals stored in respective bits of the register, each of the logic gates having a first input coupled to the respective bit of the register and a second input coupled to a bit of the register adjacent the respective bit of the register, wherein the first and last bits of the register are considered adjacent bits;
- a feedback circuit alternately coupling the output of each of the logic gates to the input of a respective bit of the register or the input of a bit of the register adjacent the respective bit of the register; and

a final results detector coupled to the outputs of the logic gates, the final results detector detecting when all of the outputs of the logic gates have the same logic level.

31. The packetized dynamic random access memory of claim 25 wherein the analysis circuit comprises a set of logic gates corresponding in number to the number of result signals stored in respective bits of the register, each of the logic gates having a first input coupled to a respective bit of the register and a second input coupled to the outputs of logic gates having respective inputs coupled to bits of the register that are positioned to one side of the bit to which the logic gate is coupled, each of the logic gates being disabled by a signal applied the second input of the gate so that only one logic gate generates an output having a first logic level responsive to signals received from respective bits of the register.

32. The packetized dynamic random access memory of claim 25 wherein the load control circuit comprises:

- a counter incremented each time one of the digital signals is stored in the latch, the counter generating count signals indicative of the count of the counter; and
- a decoder receiving the count signals, the decoder generating the phase command signals responsive to the count signals, the phase of the internal clock signal determined by each command signal corresponding to the count of the counter.

33. The packetized dynamic random access memory of claim 25, wherein the register further comprises an address circuit to store each of the results signals in the register at a location corresponding to a register address, and wherein the load control circuit further comprises an address generating circuit coupled to the register, the address generating circuit producing the register address corresponding to the count of the counter.

34. A memory device adapted to receive a plurality of input signals and generate a plurality of output signals on respective, externally accessible terminals, comprising:

- a clock generator circuit receiving an external clock signal applied to one of the terminals and generating an internal clock signal having a phase relative to the external clock signal determined by a phase command signal;
- at least one array of memory cells adapted to store data at a location determined by a row address and a column address applied to respective other of the terminals;
- a row address circuit adapted to receive and decode the row address, and select a row of memory cells corresponding to the row address responsive to a first set of command signals;
- a column address circuit adapted to receive or apply data to one of the memory cells in the selected row corresponding to the column address responsive to a second set of command signals;
- a data path circuit adapted to couple data between respective other of the terminals and the column address circuit responsive to a third set of command signals;
- a command buffer receiving memory commands on respective other of the terminals, the memory commands controlling the operation of the memory device;
- a latch coupled to one of the terminals adapted to receive a signal, the latch storing a signal applied to the terminal responsive to a transition of the internal clock signal, the latch generating a latched signal at an output;
- a load control circuit generating a plurality of phase command signals responsive to receipt of a plurality of

31

respective signals stored in the latch, each of the phase command signals corresponding to different respective phases of the internal clock signal;

an evaluation circuit coupled to the latch, the evaluation circuit receiving a plurality of latched signals and determining if each of the latched signals was accurately captured by the latch, the evaluation circuit generating a plurality of respective results signals indicative of whether each of the latched signals was accurately captured by the latch;

a register coupled to the evaluation circuit and the load control circuit, the register storing the results signals; and

an analysis circuit coupled to the register, the analysis circuit examining the results signals stored in the register and, based on the examination of the stored results signals, generating the phase command signal, the phase command signal being continuously applied to the clock generator circuit.

35. The memory device of claim **34**, wherein the analysis circuit comprises:

a plurality of logic elements corresponding in number to the number of storage locations in the register, each of the logic elements receiving a results signal stored in a respective location in the register and a results signal stored in an adjacent location in the register, each of the logic elements producing a respective compare signal resulting from a comparison of the results signals received by the logic element;

a feedback circuit coupling the compare signals back to the register for storage in the register, the feedback circuit alternately varying the location in which each compare signal is stored between two adjacent storage locations;

a final results detector detecting when the compare signals have predetermined characteristics; and

a phase command output circuit coupled to the final results detector deriving the final phase command signal from the signals stored in the register when the final results detector detects that the compare signals have the predetermined characteristics.

36. The memory device of claim **34**, wherein the analysis circuit comprises a logic circuit coupled to the register, the logic circuit identifying a set of phase command signals corresponding to a contiguous set of clock phases that caused the latch to accurately capture the latched signals, the logic circuit generating as the final phase command signal a phase command signal corresponding to a clock phases within the range of clock phases that caused the latch to accurately capture the latched signals.

37. The memory device of claim **36**, wherein the logic circuit generates as the final phase command signal a phase command signal corresponding to a clock phase in substantially the middle of a range of clock phases that caused the latch to accurately capture the latched signals.

38. The memory device of claim **36**, wherein the logic circuit identifies the internal clock phase in substantially the middle of each of a plurality of identically sized ranges of internal clock phases that caused the latch to accurately capture the latched signals, and generates as the final phase command signal a phase command signal corresponding to an identified internal clock phase at one location in the range relative to the locations of all of the other identified internal clock phases in the range.

39. The memory device of claim **34** wherein the analysis circuit comprises:

32

a plurality of logic gates corresponding in number to the number of result signals stored in respective bits of the register, each of the logic gates having a first input coupled to the respective bit of the register and a second input coupled to a bit of the register adjacent the respective bit of the register, wherein the first and last bits of the register are considered adjacent bits;

a feedback circuit alternately coupling the output of each of the logic gates to the input of a respective bit of the register or the input of a bit of the register adjacent the respective bit of the register; and

a final results detector coupled to the outputs of the logic gates, the final results detector detecting when all of the outputs of the logic gates have the same logic level.

40. The memory device of claim **34** wherein the analysis circuit comprises a set of logic gates corresponding in number to the number of result signals stored in respective bits of the register, each of the logic gates having a first input coupled to a respective bit of the register and a second input coupled to the outputs of logic gates having respective inputs coupled to bits of the register that are positioned to one side of the bit to which the logic gate is coupled, each of the logic gates being disabled by a signal applied the second input of the gate so that only one logic gate generates an output having a first logic level responsive to signals received from respective bits of the register.

41. The memory device of claim **34** wherein the load control circuit comprises:

a counter incremented each time one of the signals is stored in the latch, the counter generating count signals indicative of the count of the counter; and

a decoder receiving the count signals, the decoder generating the phase command signals responsive to the count signals, the phase of the internal clock signal determined by each command signal corresponding to the count of the counter.

42. The memory device of claim **34**, wherein the register further comprises an address circuit to store each of the results signals in the register at a location corresponding to a register address, and wherein the load control circuit further comprises an address generating circuit coupled to the register, the address generating circuit producing the register address corresponding to the count of the counter.

43. The memory device of claim **34**, wherein the input of the latch is coupled to the terminal that receives the memory commands and the output of the latch is coupled to the command buffer.

44. An integrated circuit adapted to receive a plurality of input signals and generate a plurality of output signals on respective, externally accessible terminals, comprising:

a clock generator circuit receiving an external clock signal applied to one of the terminals and generating an internal clock signal having a phase relative to the external clock signal determined by a phase command signal;

a circuit adapted to receive a plurality of input signals applied to respective other of the terminals and to generate a plurality of output signals on respective other of the terminals;

a latch coupled to one of the terminals adapted to receive an input signal, the latch storing an input signal applied to the terminal responsive to a transition of the internal clock signal, the latch generating a latched signal at an output;

a load control circuit generating a plurality of phase command signals responsive to receipt of a plurality of

respective signals stored in the latch, each of the phase command signals corresponding to different respective phases of the internal clock signal;

an evaluation circuit coupled to the latch, the evaluation circuit receiving a plurality of latched signals and determining if each of the latched signals was accurately captured by the latch, the evaluation circuit generating a plurality of respective results signals indicative of whether each of the latched signals was accurately captured by the latch;

a register coupled to the evaluation circuit and the load control circuit, the register storing the results signals; and

an analysis circuit coupled to the register, the analysis circuit examining the results signals stored in the register and, based on the examination of the stored results signals, generating the phase command signal, the phase command signal being continuously applied to the clock generator circuit.

45. The integrated circuit of claim **44**, wherein the analysis circuit comprises:

- a plurality of logic elements corresponding in number to the number of storage locations in the register, each of the logic elements receiving a results signal stored in a respective location in the register and a results signal stored in an adjacent location in the register, each of the logic elements producing a respective compare signal resulting from a comparison of the results signals received by the logic element;
- a feedback circuit coupling the compare signals back to the register for storage in the register, the feedback circuit alternately varying the location in which each compare signal is stored between two adjacent storage locations;
- a final results detector detecting when the compare signals have predetermined characteristics; and
- a phase command output circuit coupled to the final results detector deriving the final phase command signal from the signals stored in the register when the final results detector detects that the compare signals have the predetermined characteristics.

46. The integrated circuit of claim **44**, wherein the analysis circuit comprises a logic circuit coupled to the register, the logic circuit identifying a set of phase command signals corresponding to a contiguous set of clock phases that caused the latch to accurately capture the latched signals, the logic circuit generating as the final phase command signal a phase command signal corresponding to a clock phases within the range of clock phases that caused the latch to accurately capture the latched signals.

47. The integrated circuit of claim **46**, wherein the logic circuit generates as the final phase command signal a phase command signal corresponding to a clock phase in substantially the middle of a range of clock phases that caused the latch to accurately capture the latched signals.

48. The integrated circuit of claim **46**, wherein the logic circuit identifies the internal clock phase in substantially the middle of each of a plurality of identically sized ranges of internal clock phases that caused the latch to accurately capture the latched signals, and generates as the final phase command signal a phase command signal corresponding to an identified internal clock phase at one location in the range relative to the locations of all of the other identified internal clock phases in the range.

49. The integrated circuit of claim **44** wherein the analysis circuit comprises:

a plurality of logic gates corresponding in number to the number of result signals stored in respective bits of the register, each of the logic gates having a first input coupled to the respective bit of the register and a second input coupled to a bit of the register adjacent the respective bit of the register, wherein the first and last bits of the register are considered adjacent bits;

a feedback circuit alternately coupling the output of each of the logic gates to the input of a respective bit of the register or the input of a bit of the register adjacent the respective bit of the register; and

a final results detector coupled to the outputs of the logic gates, the final results detector detecting when all of the outputs of the logic gates have the same logic level.

50. The integrated circuit of claim **44** wherein the analysis circuit comprises a set of logic gates corresponding in number to the number of result signals stored in respective bits of the register, each of the logic gates having a first input coupled to a respective bit of the register and a second input coupled to the outputs of logic gates having respective inputs coupled to bits of the register that are positioned to one side of the bit to which the logic gate is coupled, each of the logic gates being disabled by a signal applied the second input of the gate so that only one logic gate generates an output having a first logic level responsive to signals received from respective bits of the register.

51. The integrated circuit of claim **44** wherein the load control circuit comprises:

- a counter incremented each time one of the signals is stored in the latch, the counter generating count signals indicative of the count of the counter; and
- a decoder receiving the count signals, the decoder generating the phase command signals responsive to the count signals, the phase of the internal clock signal determined by each command signal corresponding to the count of the counter.

52. The integrated circuit of claim **44**, wherein the register further comprises an address circuit to store each of the results signals in the register at a location corresponding to a register address, and wherein the load control circuit further comprises an address generating circuit coupled to the register, the address generating circuit producing the register address corresponding to the count of the counter.

53. The integrated circuit of claim **44**, wherein the integrated circuit comprises a memory device having a command buffer receiving memory commands on respective terminals of the memory device, the memory commands controlling the operation of the memory device.

54. The integrated circuit of claim **53**, wherein the input of the latch is coupled to the terminal that receives the memory commands and the output of the latch is coupled to the command buffer.

55. A computer system, comprising:

- a processor having a processor bus;
- an input device coupled to the processor through the processor bus adapted to allow data to be entered into the computer system;
- an output device coupled to the processor through the processor bus adapted to allow data to be output from the computer system; and
- a dynamic random access memory coupled to the processor bus adapted to allow data to be stored, adapted to receive a plurality of input signals and generate a plurality of output signals on respective, externally accessible terminals, the dynamic random access memory comprising:

a clock generator circuit receiving an external clock signal applied to one of the terminals and generating an internal clock signal having a phase relative to the external clock signal determined by a phase command signal;

at least one array of memory cells adapted to store data at a location determined by a row address and a column address applied to respective other of the terminals;

a row address circuit adapted to receive and decode the row address, and select a row of memory cells corresponding to the row address responsive to a first set of command signals;

a column address circuit adapted to receive or apply data to one of the memory cells in the selected row corresponding to the column address responsive to a second set of command signals;

a data path circuit adapted to couple data between respective other of the terminals and the column address circuit responsive to a third set of command signals;

a command buffer receiving memory commands on respective other of the terminals, the memory commands controlling the operation of the memory device;

a latch coupled to one of the terminals adapted to receive a signal, the latch storing a signal applied to the terminal responsive to a transition of the internal clock signal, the latch generating a latched signal at an output;

a load control circuit generating a plurality of phase command signals responsive to receipt of a plurality of respective signals stored in the latch, each of the phase command signals corresponding to different respective phases of the internal clock signal;

an evaluation circuit coupled to the latch, the evaluation circuit receiving a plurality of latched signals and determining if each of the latched signals was accurately captured by the latch, the evaluation circuit generating a plurality of respective results signals indicative of whether each of the latched signals was accurately captured by the latch;

a register coupled to the evaluation circuit and the load control circuit, the register storing the results signals; and

an analysis circuit coupled to the register, the analysis circuit examining the results signals stored in the register and, based on the examination of the stored results signals, generating the phase command signal, the phase command signal being continuously applied to the clock generator circuit.

56. The computer system of claim **55**, wherein the analysis circuit comprises:

a plurality of logic elements corresponding in number to the number of storage locations in the register, each of the logic elements receiving a results signal stored in a respective location in the register and a results signal stored in an adjacent location in the register, each of the logic elements producing a respective compare signal resulting from a comparison of the results signals received by the logic element;

a feedback circuit coupling the compare signals back to the register for storage in the register, the feedback circuit alternately varying the location in which each compare signal is stored between two adjacent storage locations;

a final results detector detecting when the compare signals have predetermined characteristics; and

a phase command output circuit coupled to the final results detector deriving the final phase command signal from the signals stored in the register when the final results detector detects that the compare signals have the predetermined characteristics.

57. The computer system of claim **55**, wherein the analysis circuit comprises a logic circuit coupled to the register, the logic circuit identifying a set of phase command signals corresponding to a contiguous set of clock phases that caused the latch to accurately capture the latched signals, the logic circuit generating as the final phase command signal a phase command signal corresponding to a clock phase within the range of clock phases that caused the latch to accurately capture the latched signals.

58. The computer system of claim **57**, wherein the logic circuit generates as the final phase command signal a phase command signal corresponding to a clock phase in substantially the middle of a range of clock phases that caused the latch to accurately capture the latched signals.

59. The computer system of claim **57**, wherein the logic circuit identifies the internal clock phase in substantially the middle of each of a plurality of identically sized ranges of internal clock phases that caused the latch to accurately capture the latched signals, and generates as the final phase command signal a phase command signal corresponding to an identified internal clock phase at one location in the range relative to the locations of all of the other identified internal clock phases in the range.

60. The computer system of claim **55** wherein the analysis circuit comprises:

a plurality of logic gates corresponding in number to the number of result signals stored in respective bits of the register, each of the logic gates having a first input coupled to the respective bit of the register and a second input coupled to a bit of the register adjacent the respective bit of the register, wherein the first and last bits of the register are considered adjacent bits;

a feedback circuit alternately coupling the output of each of the logic gates to the input of a respective bit of the register or the input of a bit of the register adjacent the respective bit of the register; and

a final results detector coupled to the outputs of the logic gates, the final results detector detecting when all of the outputs of the logic gates have the same logic level.

61. The computer system of claim **55** wherein the analysis circuit comprises a set of logic gates corresponding in number to the number of result signals stored in respective bits of the register, each of the logic gates having a first input coupled to a respective bit of the register and a second input coupled to the outputs of logic gates having respective inputs coupled to bits of the register that are positioned to one side of the bit to which the logic gate is coupled, each of the logic gates being disabled by a signal applied the second input of the gate so that only one logic gate generates an output having a first logic level responsive to signals received from respective bits of the register.

62. The computer system of claim **55** wherein the load control circuit comprises:

a counter incremented each time one of the signals is stored in the latch, the counter generating count signals indicative of the count of the counter; and

a decoder receiving the count signals, the decoder generating the phase command signals responsive to the count signals, the phase of the internal clock signal

37

determined by each command signal corresponding to the count of the counter.

63. The computer system of claim **55**, wherein the register further comprises an address circuit to store each of the results signals in the register at a location corresponding to a register address, and wherein the load control circuit further comprises an address generating circuit coupled to

38

the register, the address generating circuit producing the register address corresponding to the count of the counter.

64. The computer system of claim **55**, wherein the input of the latch is coupled to the terminal that receives the memory commands and the output of the latch is coupled to the command buffer.

* * * * *

UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

PATENT NO. : 5,953,284
DATED : September 14, 1999
INVENTOR(S) : Baker et al.

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

“the is NAND”

-- the NAND --

“IMTRES”

-- INITRES --

Signed and Sealed this

First Day of May, 2001

Attest:



NICHOLAS P. GODICI

Attesting Officer

Acting Director of the United States Patent and Trademark Office